SPIRE DRCU Programme Review

4 March 2003, SAp, Saclay

Review Board Report

SPIRE-UCF-REP-001573

24 March 2003

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1. Review objectives and organisation

1.1 Objectives

The objectives of this review were:

- (i) to close out the DRCU Documentation Review, with special attention to interfaces;
- (ii) to review the DRCU development plan and schedule with respect to the instrument delivery schedule, with the aim of maintaining on-time delivery of the instrument PFM;
- (iii) to demonstrate that the risks associated with the warm electronics programme are understood and can be controlled;
- (iv) to examine and set in place the necessary resources and management/communication practices to allow the development plan to be effectively implemented;
- (v) to prepare for and cover most relevant issues for the instrument IHDR (which should then be rather routine for the DRCU).

1.2 Participants and Review Board

The list of participants in the review is given in Annex A. The Review Board comprised

Matt Griffin (chair)	Cardiff University	SPIRE PI
Eric Sawyer	RAL	SPIRE Hardware Project Manager
Bruce Swinyard	RAL	SPIRE Instrument Scientist
John Delderfield	RAL	SPIRE System Engineer
Riccardo Cerulli	IFSI	DPU Design Engineer
Astrid Heske	ESA, ESTEC	SPIRE Instrument System Engineer
Filippo Marliani	ESA, ESTEC	Electronics Engineer
Yvan Blanc	CNES	
Kareine Mercier	CNES	
Ray Carvell	PPARC	UK Herschel/Planck Programme Director
Chris Whitford	Leicester University	Independent expert
Kees Wafelbakker	SRON, Groningen	Independent Expert *

* Owing to domestic problem, Kees Wafelbakker was unable to attend the review meeting.

1.3 Review format

The review documentation package was issued on 19 February. The list of documents is attached as Annex B. The documents are available in the SPIRE area on *Livelink*. The review meeting, involving presentations, questions and answers, and meeting of the Review Board, was held on March 4 at SAp, Saclay. The review presentations are given in Annex C.

2. Review Board conclusions

2.1 Summary and recommendations

- 1. The Board was very impressed by the excellent progress made by the DRCU team since the IBDR, and was particularly pleased to note:
 - the thoroughness and high standard of the documentation;
 - the detailed thermal, mechanical and electrical modelling work presented;
 - the progress made in developing and testing the DCU EM.

Whilst the remainder of this report is mainly about problem areas, these achievements and successes are fully acknowledged.

2. A number of detailed technical comments have been made in the course of the documentation review that has been taking place prior to the meeting. The current status of these is summarised in Annex D Additional technical comments were made in the course of the review meeting, and are summarised in Section 3 below. These points should be addressed as part of routine work, and a consolidated summary

prepared for the IHDR. CEA and the SPIRE Project Team are expected to close out the documentation review formally prior to the IHDR.

3. The Review Board is greatly concerned that the current DRCU schedule is not compatible with an ontime delivery of the SPIRE instrument. Several scenarios were presented and considered during the review. These schedule scenarios need to be analysed in further detail, in particular the boundary conditions, the underlying assumptions and the risks involved need to be critically assessed. All efforts should be made to retain the Instrument FM and CQM delivery dates. Decoupling of the QM and FM programmes may be unavoidable for the DRCU (as is already being done in other areas of the Hershcel/Planck project), and the associated risks need to be assessed.

The Board notes that the different scenarios do not diverge until the middle of 2003. It is recommended that the issue is fully reviewed and understood well before the SPIRE IHDR in July, to be able to close it during that review.

- 4. The late availability of the PSU is a matter of serious concern, both from the schedule point of view and because it poses technical risks in that any system-level problems associated with the compatibility of the PSU with the rest of SPIRE would arise very late in the programme. The Board recommends that CEA examine, as a high priority, the possibility of procuring a second PSU Engineering Model that could be delivered to RAL for use in instrument tests.
- 5. SPIRE is a very sensitive instrument with extremely low noise levels and a long cable harness between the FPU and the warm units. The Board did not see evidence that all possible measures are being taken to ensure that the DRCU and the rest of the system it will meet the specification. This incorporates system issues, not just DRCU design aspects. In the context of the DRCU programme, the Board recommends that:

(i) a breadboard test of the DRCU EMC susceptibility be considered;

(ii) the PSU specification be extended (probably in consultation with the selected contractor) to incorporate a more detailed treatment of its noise performance.

- 6. The worst case analysis has not been done for all parts of the system. Eliminating or delaying part of the analysis to a later stage increases risk. The status and CEA policy with respect to the WCA should be clearly stated and justified at the IHDR.
- 7. It is recognised that in obtaining and maintaining the necessary staff resources to implement a programme such as this, the availability of specialised skills and key individuals can be a significant limitation, in addition to financial considerations. The Board recommends that the DRCU team plans actively to ensure the future availability of key staff to the maximum extent possible.
- 8. The Board assesses the success of the review with respect to the stated objectives as follows:

	Objective	Assessment
i	Close out the DRCU Documentation Review, with special attention to interfaces	Achieved, with various minor issues to be addressed as normal work.
ii	Review of the DRCU development plan and schedule with respect to the instrument delivery schedule, with the aim of maintaining on-time delivery of the instrument PFM.	In progress, and remains a high priority for the period between now and the IHDR. Close-out before the IHDR is needed.
iii	Demonstration that the risks associated with the warm electronics programme are understood and can be controlled.	In progress, and remains as a high priority for the IHDR
iv	Examine and setting in place the necessary resources and management/communication practices to allow the development plan to be effectively implemented	Resources are limited at CEA and LAM, and within the SPIRE Project Team. Communications between the teams are now happening in a more effective manner than in the past, and it will be important to maintain this.
v	Preparation for and coverage of the most relevant issues for the instrument IHDR (which should then be rather routine for the DRCU).	Largely achieved - at the IHDR, the schedule/ programmatic issues will be at the forefront.

2.2 List of technical issues

- 1. It appears from the documentation that the effect of the input current noise in the source impedance has not been included in the noise analysis. According to the MAT-02 data sheet, the noise, at 0.25 mA Ic, is about 1.5 pA Hz^{-1/2}. Theoretically it should be 0.4 pA Hz^{-1/2}. From a practical point of view, it could be measured: with a small source resistance, the measured value is voltage noise; for a larger value, it is the Johnson noise of the resistor; and for a very large value it is the current noise.
- 2. From the DCU design document, the noise from the final amplifiers after the multiplexing also looks to be non-compliant. The analysis on p.75 of the DCU Design Document is not clear on this point.
- 3. A PSU configuration that tends to inject noise back to main bus rather than towards the unit is appropriate in this application the adoption of such a configuration should be discussed with the PSU provider.
- 4. The manner in which the JPL detector requirements are apportioned in the design and converted to PSU specifications is not detailed in the documentation. A technical note should be produced for the IHDR giving proof by analysis that the DRCU design plus the PSU spec will result in a system that will meet the requirements.
- 5. Because of the multiplexing, inter-channel interference may occur. To achieve 16-bit resolution, this needs to be tested, by comparing the measurements on one channel when the immediately preceding channel is switched from minimum to maximum. A small amount of interference can be compensated.
- 6. It is recommended that RC filters be incorporated on the inputs of the MAT-02 amplifiers. This will give added ESD protection and also filter out high frequency interference above the frequency where the common mode rejection of the amplifier drops. A possible approach would be to add 100 Ω in series with each input and 100 pF behind each 100 Ω to ground. Filter connectors can also be considered. Filter connectors may be long-lead-items and so if foreseen should be ordered early.
- 7. The electrical system is vulnerable to noise on the bias generators and on the JFET supplies, and these are issues which should be addressed, either by analysis or test. There should be a specification agreed between CEA and JPL for the noise on the JFET bias supplies.
- 8. The sensitivity of the signal chain to noise from the DC-DC converters does not seem to have been quantified. Therefore any specification put on the converters must be a guess. Whatever is specified for the converters, the electronics should be tested against this, or alternatively, tests on the electronics should drive the converter specification
- 9. With the long cable harness between the DRCU and the focal plane, interference is a big issue. This has to be looked at from a system point-of-view, and the DRCU is only a part of this. There are three main sources of noise: low frequency magnetic pickup, radiated RF and conducted structure noise. Shields provide very little attenuation of low frequency magnetic fields. The main defence is to keep everything balanced and use twisted pair wiring everywhere (the pitch and evenness of the twisting is important. RF fields have an effect through direct heating of the bolometers or rectification in active devices, which is why filters at the amplifier inputs are important. Structure currents may be the major source of noise. Some analysis should be done, and room temperature testing carried out to get some handle on how effective the protective measures are.
- 10. Any single-point failures which would affect more that small numbers of pixels (~ 10) should be flagged in the FMECA and the associated risk approved at system level.
- 11. The FCU interfaces must not compromise grounding scheme by returning currents along ground lines. All drives must work differentially across power supplies. This was stated during the presentations, but is not clearly indicated in the FCU documentation. Figure 19 in the SCU description could imply otherwise, and this needs clarification.
- 12. The CEA FPU simulator must be ground isolatable to simulate an isolated FPU. It is grounded by attachment to the DRCU.
- 13. Allowing two weeks only for verification of the EM converters is very much success orientated.
- 14. To aid detailed design, particularly by LAM for the MCU, there must be a budget for the temperature drop across the stacked elements through the PSU into the FCU.

- 15. A characterisation is needed of the time delay versus frequency introduced by the electronics chain (analogue chain + mux/digitisation). This will be important to know whether to it take into account for relative SMEC/pixel datation.
- 16. The DPU-DRCU interface clock can be up to 2.5 MHz. Any relevant documentation should be corrected to reflect this.
- 17. There is a large peak in power delivered to the FPU during the cooler recycle. The corresponding peak power in the FCU should be quantified to check that it poses no problem for the thermal behaviour of the unit.
- 18. Additional damping is under consideration for the mechanisms. It is necessary to check whether there will be any appreciable increase in drive power requirements due to the extra damping. If this is significant in the FPU over and above the present power budgets, it may not be acceptable, and might also generate excessive harness dissipation.
- 19. The deletion of the BSM latch is yet to be confirmed by the Project, so the electronics design should not yet assume that.
- 20. Some DCU connectors show Faraday shield pins, but these pins are either 0 V or N/C. The Faraday shield is terminated to DRCU connectors by tails inside backshells to the connector body. The connector section of the DRCU ICD should be prefixed with a note that the HDD is applicable.

3. List of Annexes

- Annex A: List of participants
- Annex B: List of documents provided for the review
- Annex C: Review presentations
- Annex D: Status of technical comments on review documents

SPIRE DRCU Programme Review

4 March 2003, SAp, Saclay Review Board Report SPIRE-UCF-REP-001573 Annexes

Annex A

List of Participants

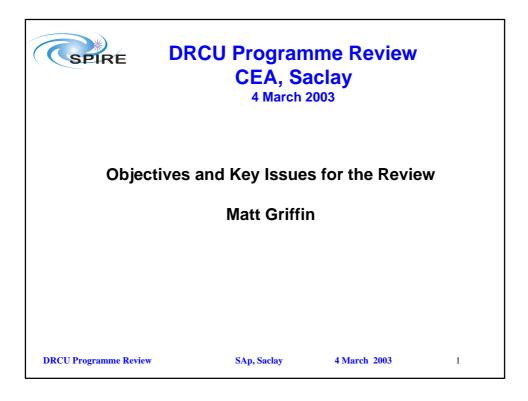
Jean-Louis	Augueres	CEA
Jean-Paul	Baluteau	LAM
Yvan	Blanc	CNES
Christophe	Cara	CEA
Ray	Carvell	PPARC
Riccardo	Cerrulli	IFSI
John	Delderfield	RAL
Jean	Fontignie	CEA
Matt	Griffin	Cardiff University
Astrid	Heske	ESA
Filippo	Marliani	ESA
Karine	Mercier	CNES
Michel	Mur	CEA
De Antoni	Philippe	CEA
Frederic	Pinsard	CEA
Diminique	Pouliquen	LAM
Eric	Sawyer	RAL
Bruce	Swinyard	RAL
Henri	Triou	CEA
Laurent	Vigroux	CEA
Chris	Whitford	Leicester University

Annex B List of Documents reviewed

title	doc number	actual issue	status
Management plan for the Herschel project.	SAp-FIRST-JLA-0038-01	4.0 23/01/2003	ok
DRCU & WIH Development Plan	SAp-SPIRE-JLA-0047-01	4.0 29/01/2003	ok
SPIRE product tree	SAp-SPIRE-DR-0094-03	1.0 21/01/2003	ok
WBS Herschel	SAP-FIRST-DR-0043-01	2.1 30/11/2001	ok
WBS SPIRE	SAP-FIRST-DR-0045-01	2.1 30/11/2001	ok
SPIRE DRCU QM1master schedule	SAp-FIRST-DR-105-01	1 18/02/2003	ok
DRCU Specifications document	SAp-SPIRE-Cca-0025-00	1.0 14/02/2003	ok
	(SPIRE-SAP-PRJ-000461)		
DRCU ICD	SAp-SPIRE-Cca-0075-02	1.0 14/02/2003	ok
	(SPIRE-SAP-PRJ-000451)		
DRCU DPU ICD	SAp-SPIRE-Cca-0076-02	1.0 14/02/2003	ok
	(SPIRE-SAP-PRJ-001364)		
DCU design document	SAp-SPIRE-FP-0063-02	0.3 18/02/2003	ok
Test plan DAQ IF	SAp-SPIRE-FP-0067-02	0.1 draft	ok
Test plan BIAS	SAp-SPIRE-FP-0066-02	0.1 draft	ok
Test plan LIA P	SAp-SPIRE-FP-0064-02	0.1 draft	ok
Test plan LIA S	SAp-SPIRE-FP-0065-02	0.1 draft	ok
SPIRE test configuration	SAp-SPIRE-LD-0015-01	3.0 08/2001	to be provided at review
FPU simulator specs for DCU / SCU test	SIG-SPIRE-PdA-0030-01	03 14/02/2003	ok
SPIRE LTU specifications	SAp-SPIRE-FD-0071-02	1.0 22/04/2002	ok
DRCU AIV Plan	SAp-SPIRE-HT-0082-02	2.0 03/02/2003	ok
DRCU EM/QM1 preliminary test plan	SAp-SPIRE-HT-0088-02	0.1 14/02/2003	ok
SCU design document	SEDI-SCU-MM-2002-1	0.7 17/02/2003	ok
PSU SPIRE specification	SAp-SPIRE-DS-012-02	1.1 11/12/2002	ok
PA Plan	SAP-GERES-Flo-436-00	1.0 07/11/2000	ok
DPL	SAp-SPIRE-NC-0061-02	1.0 13/02/2003	ok
DML	SAp-SPIRE-NC-0060-02	1.0 13/02/2003	ok
DMPL	SAp-SPIRE-NC-0100-02	1.0 13/02/2003	ok
DCL	SAp-SPIRE-VM-0098-02	14 10/02/2003	ok
Synthesis note about DRCU FMEA and reliability	SAp-SPIRE-JF-0099-03	0.1 10/02/2003	ok
WCA (and derating??)	will be performed later		

Annex C

Review Meeting Presentations



Cs	PIRE Objectives		
1.	 Close out of the DRCU documentation review (= DDR), with special attention to interfaces 		
2.	Review the DRCU development plan and schedule with respect to the instrument delivery schedule, with the aim of maintaining on-time delivery of the instrument PFM		
3.	 Demonstrate that the risks associated with the warm electronics programme are understood and can be controlled 		
4.	Consider the necessary resources and management/ communication practices to allow the development plan to be effectively implemented		
5.	Prepare for and cover most relevant issues for the instrument IHDR (to take place in July), which should then be rather routine for the DRCU)		
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SPIRE	Review Board	
SPIRE Project	Matt Griffin (chair) Bruce Swinyard Eric Sawyer John Delderfield	
IFSI	Riccardo Cerulli	
ESA	Astrid Heske Filippo Marliani	
PPARC	Ray Carvell	
CNES	Yvan Blanc	
Experts	Kees Wafelbakker Chris Whitford	
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SPIRE			Agenda		
9:00	9:10	10	Introduction and logistics	Jean-Louis Augueres	
9:10	9:25	15	Objectives and key issues for the review	Matt Griffin	
9:25	9:40	15	Instrument overview	Bruce Swinyard	
9:40	10:00	20	DRCU design overview	Christophe Cara	
10:00	10:15	15	DCU	Frederic Pinsard	
10:15	10:35	20	Coffee		
10:35	10:50	15	SCU	Michel Mur	
10:50	11:05	15	MCU	Dominique Pouliquen	
11:05	11:20	15	Power Supply Specification	Dominique Schmitt	
11:20	11:35	15	DDR close-out	Eric Sawyer	
11:35	11:55	20	Instrument Development Plan and Schedule	Eric Sawyer	
11:55	12:10	15	Instrument electronics AIV plan	Eric Sawyer	
12:10	12:30	20	DRCU AIV plan	Henri Triou	
12:30	13:00	30	Questions and clarifications		
13:00	14:30	90	Lunch		
14:30	14:50	20	DRCU Development and Procurement Plan	Jean-Louis Augueres	
14:50	15:00	10	Institute staffing and management	Jean-Louis Augueres	
15:00	15:30	30	Questions and clarifications		
15:30	15:50	20	Coffee		
15:50	16:50	60	Review Board meeting		
16:50	17:00	10	Review Board feedback		
17:00			Meeting End		
DRCU Prog	ramme Re	view	SAp, Saclay 4 March	2003 4	



SPIRE Instrument Overview

Bruce Swinyard

RAL

DRCU Programme Review



Instrument Design Drivers

- Photometer (200-670 microns)
 - Deep mapping of extra-galactic sky with highest efficiency and largest possible field of view
 - Multi-band coverage with simultaneous observation
 - Point and compact source observation with high efficiency
- Spectrometer (200- >610 microns)
 - Sensitivity optimised for point/compact source spectroscopy
 - Imaging spectroscopy with maximum available field of view
 - Wide wavelength coverage
 - Variable spectral resolution (few x 10 to few x 100)

Both

- Thermal background dominated by the Herschel telescope
- Simplicity, affordability, reliability, ease of operation
- Complementary to other Herschel instruments and other facilities

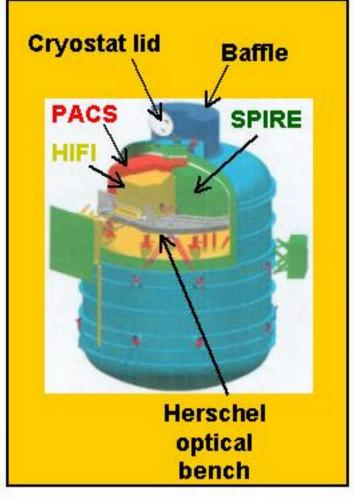


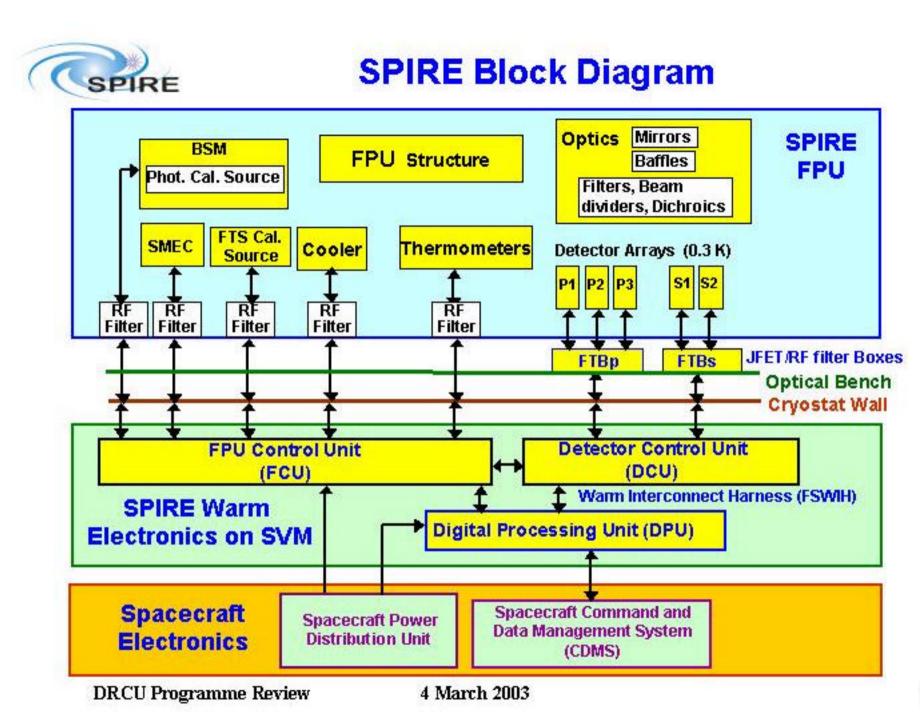
Instrument Summary

3-band imaging photometer

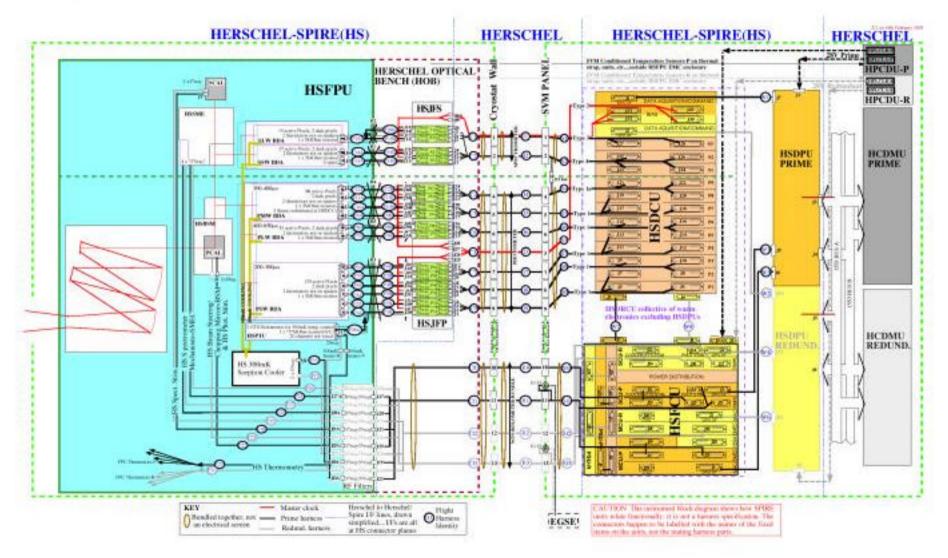
- 250, 360, 520 µm (simultaneous)
- λ/Δλ ~ 3
- 4 x 8 arcminute field of view
- Diffraction limited beams (17, 24, 35")
- Imaging FTS
 - mىر 670 200
 - > 2 arcminute field of view
 - Δσ = 0.4 cm⁻¹ (goal 0.04 cm⁻¹) (λ/Δλ ~ 20 - 100 (1000) at 250 μm)
- Design features
 - Sensitivity limited by thermal emission from the telescope (80 K; ε = 4%)
 - ³He cooled detector arrays (0.3 K)
 - Feedhorn-coupled spider web NTD bolometers
 - Minimal use of mechanisms
 - Beam steering mirror, FTS mirror drive
 - No on-board data processing

DRCU Programme Review





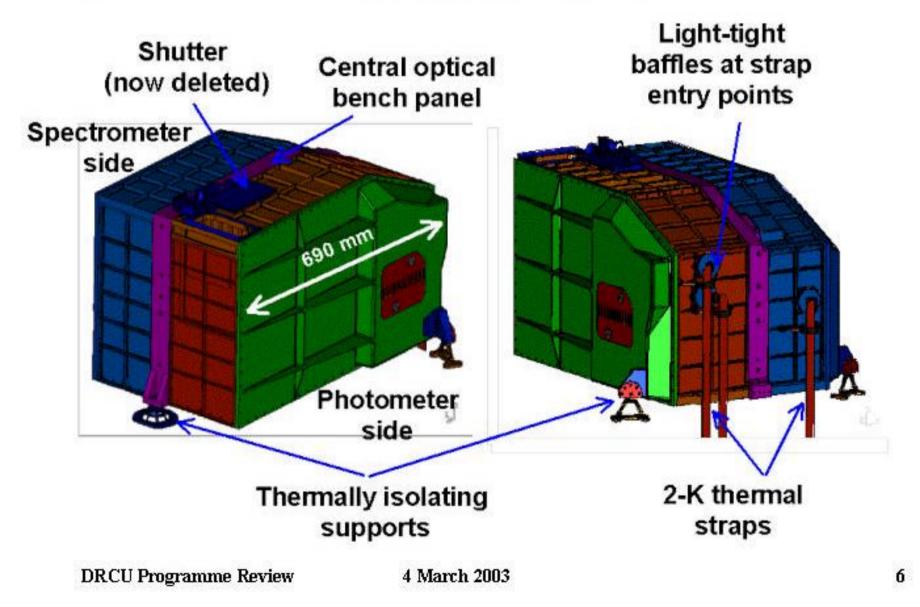




DRCU Programme Review

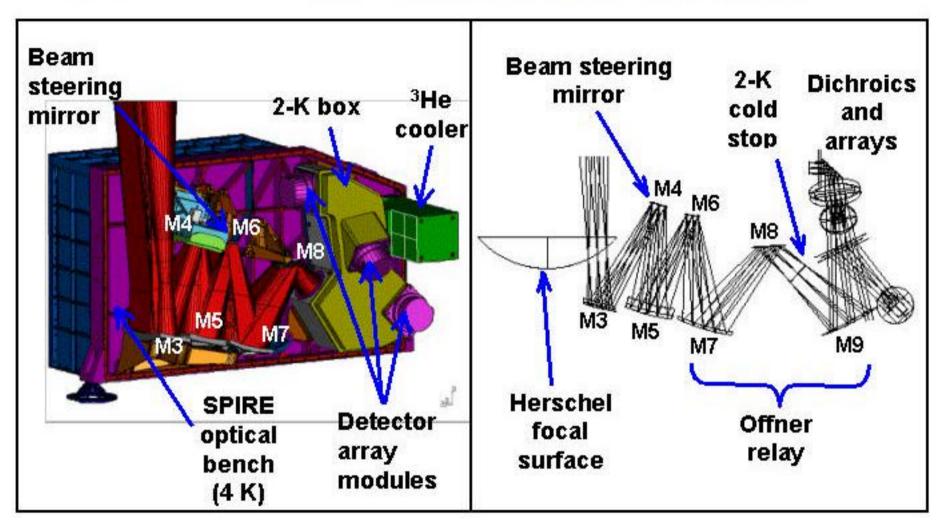


Focal Plane Unit



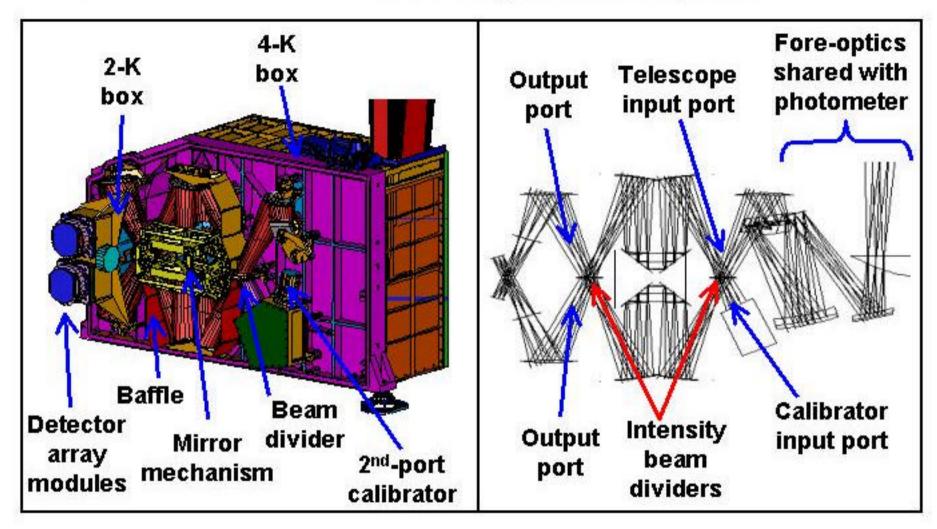


Photometer Layout and Optics



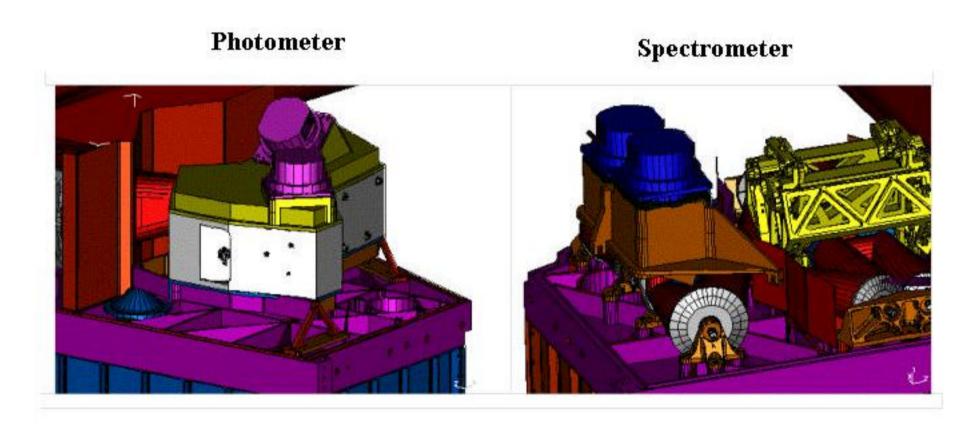


FTS Layout and Optics





2-K Enclosures for Detector Modules



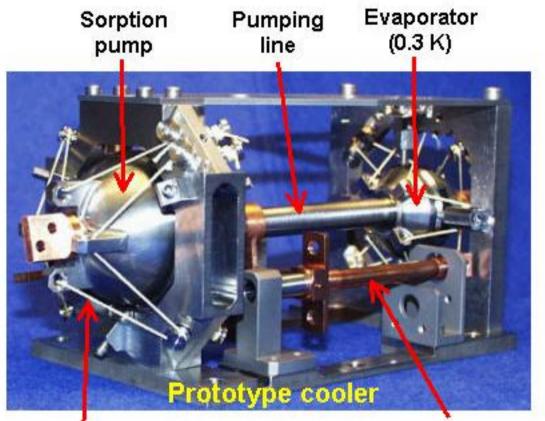
DRCU Programme Review



- Cold stage temp.
 < 280 mK
- Hold time > 46 hrs
- Cycle time < 2 hrs
- Average load on ⁴He tank < 3 mW
- Heat lift provided to detector arrays > 10 μW
- Gas-gap heat switches (no moving parts)
- Driven by SCU DPU controls operations

DRCU Programme Review

³He Cooler

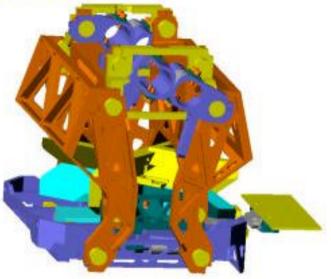


Kevlar suspension Gas-gap heat switch



FTS Mechanism

- Double parallelogram with toothless gear
- Movement range -0.3 to 3.5 cm
- Measurement of position by optical encoder with high resolution 10 nm
- Over part of range have backup LVDT with 100 nm resolution
- Signal conditioning; motor drive and speed control is done by MCU
- Start; stop and movement range controlled by DPU







FTS Observing Modes

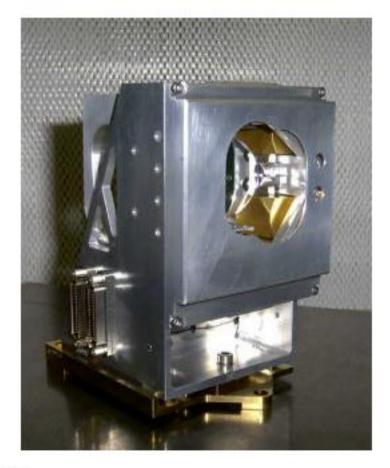
- Continuous scan:
 - Mirror scan rate = 0.5 mm s⁻¹
 - Signal frequency range = 3 10 Hz
 - Calibrator in 2nd port nulls telescope background
- Step-and-integrate:
 - 2nd port calibrator is off
 - Mirror stepped with integration at each position
 - BSM chops on sky
- Point source spectroscopy/spectrophotometry
 - Telescope pointing fixed
 - Background characterised by adjacent pixels
- Imaging spectroscopy
 - Beam steering mirror adjusts pointing between scans to acquire fully-sampled spectral image

DRCU Programme Review



Beam Steering Mirror

- Two axis mechanism
- Chop axis has +-2.5 degree throw at up to 2 Hz
- Jiggle axis has +-0.5 degree throw at up to 0.5 Hz
- Basic control done in MCU – DPU controls timing

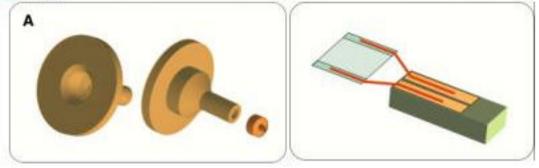




Calibration Sources

- Two calibration sources are used – SCAL and PCAL
- PCAL mounted on the BSM
- Heaters and thermistors conditioned by SCU
- Timing and temperature control done using DPU

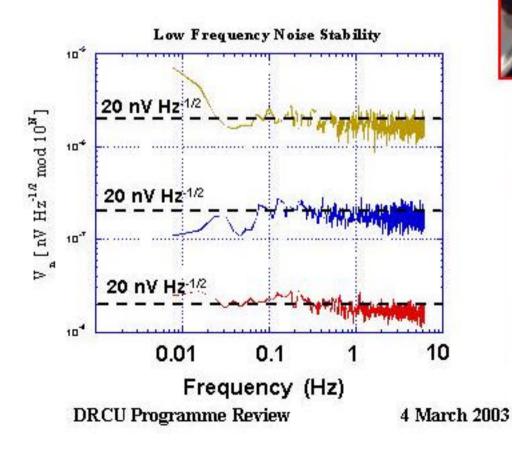


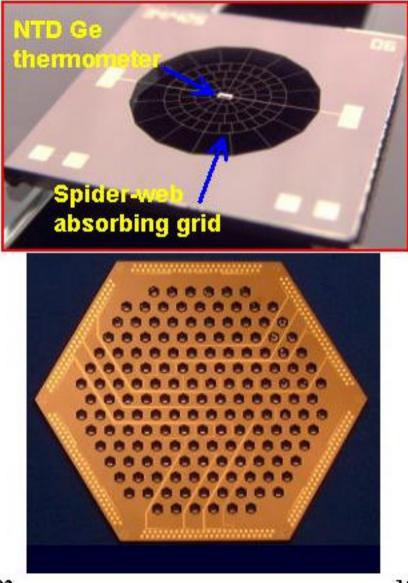




NTD Ge Bolometer Arrays (Caltech/JPL)

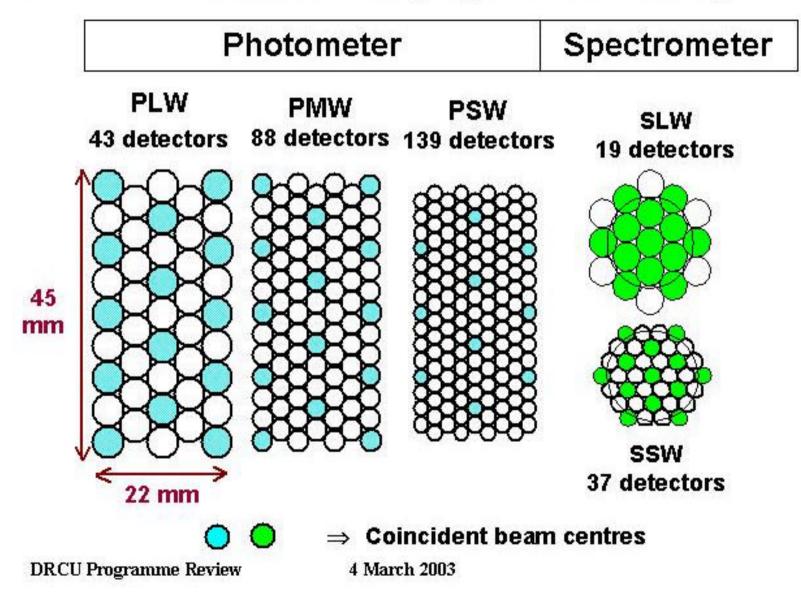
- NEP ~ 3 x 10-17 W Hz-1/2
- 120-K Si JFET readout
- 1/f noise knee < 100 mHz





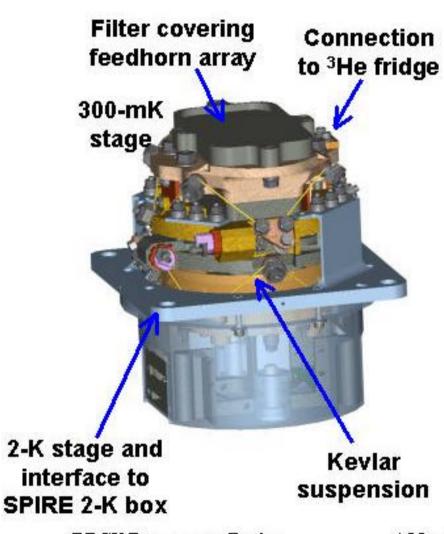


Detector Arrays (2F_l Feedhorns)

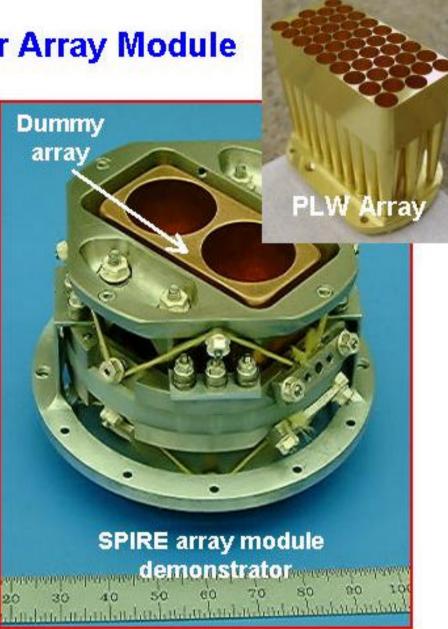




Bolometer Array Module

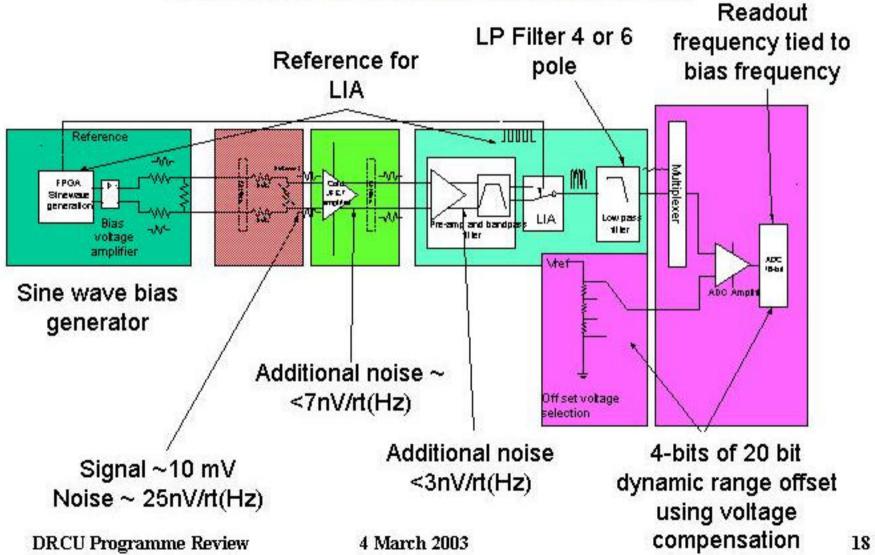


DRCU Programme Review



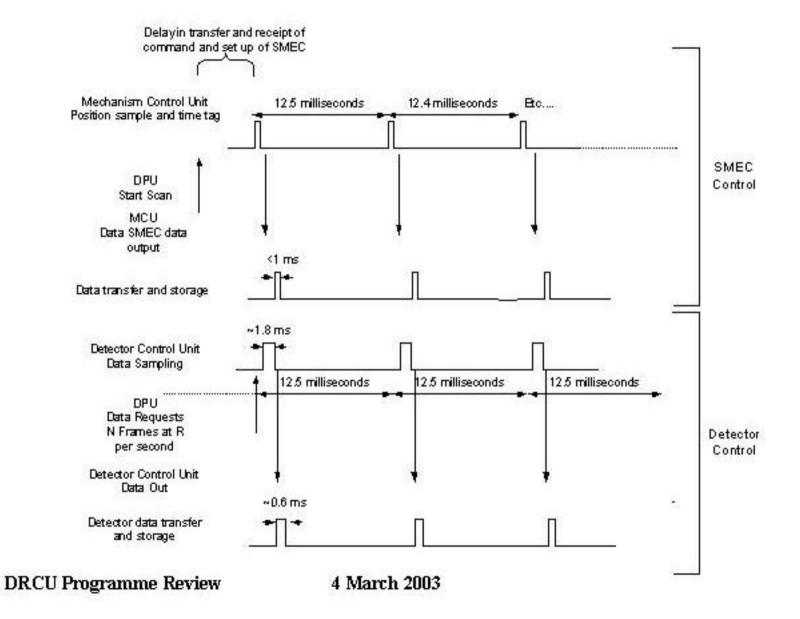


Overview of Detector Electronics





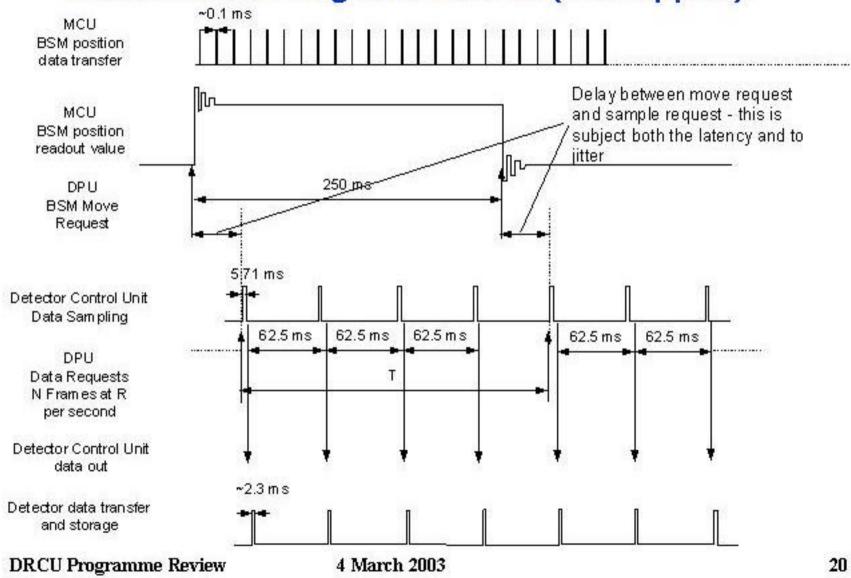
Instrument timing and control (S)



19



Instrument timing and control (P chopped)







DRCU Design

presented by $C_{\hbox{\scriptsize \bullet}}$ CARA DRCU Engineer

contributors: V. MAUGUEN EEE engineer T. TOURRETTE Mech. engineer





Overview

- The *DRCU* is a two box units:
 - The FPU Control Unit (FCU) comprises
 - The FTS and BSM associated electronics which constitutes the Mechanisms Control Unit (MCU)
 - The Calibrators, cooler and thermometer associated electronics which constitutes the Subsystems Control Unit (SCU)
 - The Power Supply Unit (PSU)
 - The Detector Control Unit (DCU) comprises analog and digital electronics exclusively devoted to bolometers operation
- Additionally power distribution between boxes is achieved by means of harness:
 - FCU to FCU (includes on/off commands for MCU & part of DCU)
 - FCU to DCU (belongs to the WIH)





Origin of Specifications

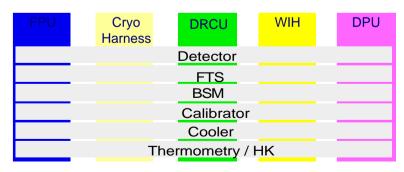
• from S/C:

- IID-A
- IID-B

2 from System level:

- Instrument Requirement Document
- Instrument Grounding Diagram
- Instrument Harness Definition

8 from sub-systems level:





Electrical Design (1)

• Overall architecture:

- **3+1 electrically independent subunits**
 - **DCU: Detector Electronics**
 - **MCU: FTS/BSM Electronics**
 - **SCU:** Calibrator/Cooler/Thermometry Electronics
 - + **PSU:** DCU/MCU/SCU power supplies
- Redundancy/Reliability

Architecture is driven by 2 main constrains:

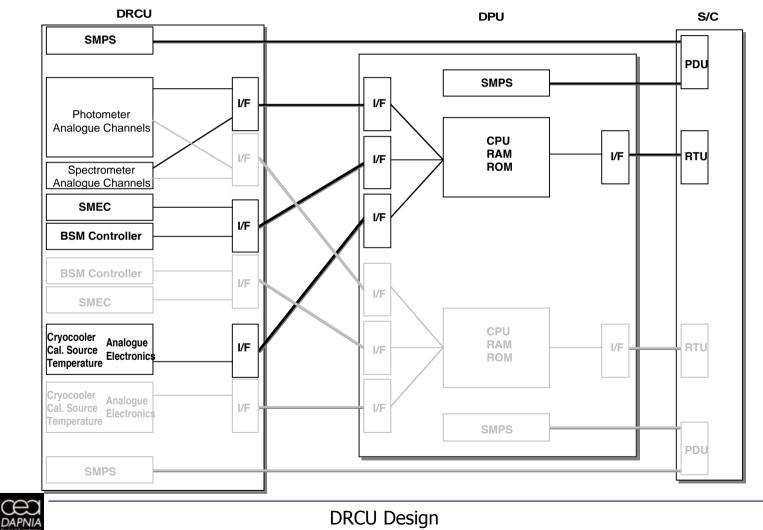
- Avoid as much as possible Single Point Failure
- Cold redundancy is applied when possible
- Limit failure propagation
- see DCU/LIA over-current protection





Electrical Design (2)

main configuration



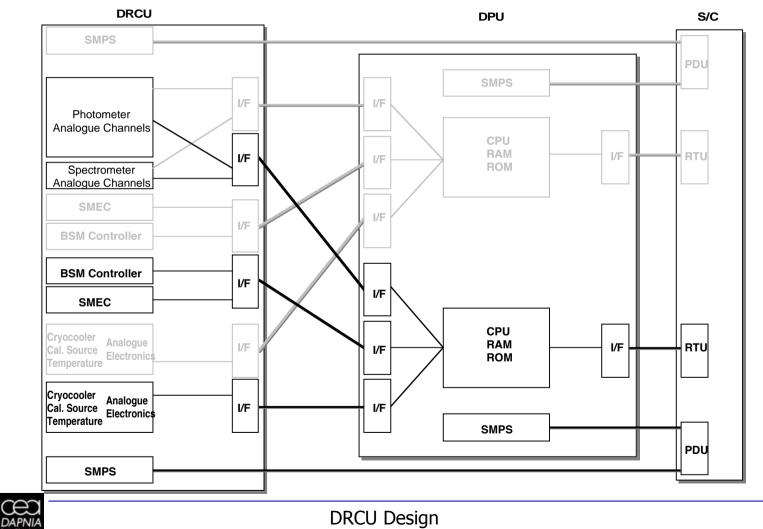
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6

Electrical Design (2)

redundant configuration



Electrical Design (3)

B FPU / DRCU interfaces

- Most of interfaces are balanced
- Better rejection of external perturbations
- Common mode rejection optimized by balancing interface impedance where interface is single ended

ORCU / DPU interfaces

- Data Interface timing optimization for 1 to 2.5 MHz operation
- DCU data packet pixel re-arranged
- MCU data packet redefined for more flexibility
- Command list updated for the 3 S/S





Electrical Design (4)

Grounding scheme

- Finalized Q4/2002
- Goal: to limit propagation toward the FPU of noise sources in SVM (digital electronics, digital interfaces, DC/DC converters, ...)
- DRCU electronics is referenced to chassis at DCU and FCU level
- Board ground planes are connected to stiffeners
- Stiffeners/Case contact is low resistance
- Case/SVM panel is low resistance
- Return path impedance for induced perturbation is minimized



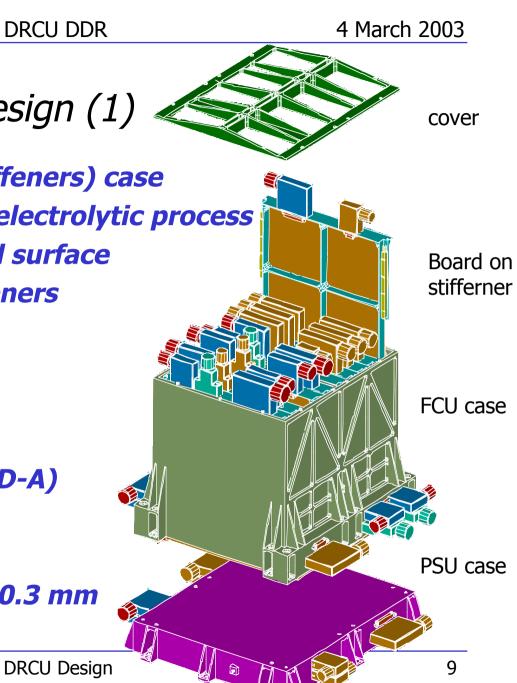


Mechanical/thermal Design (1)

- 1.5 mm Aluminum (+ stiffeners) case
- Case assembly based on electrolytic process
- Anodic oxidations treated surface
- Boards mounted on stiffeners (screws + glue)
 - Modeling shows:

SPIRE

- Case eigen frequency: 500 Hz (>140 Hz / IID-A)
- **Board frequency:** 304 Hz
- Board deformation: ≤ 0.3 mm



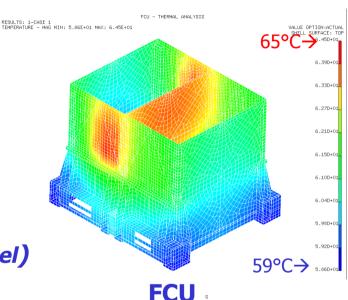


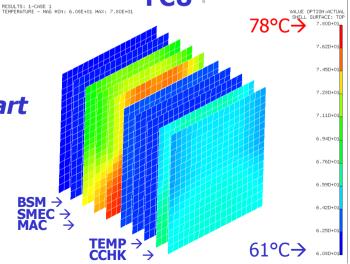


Mechanical/Thermal Design (2)



- Large contact area with panel:
 - More than 28000 cm2 for DCU
 - More than 100000 cm2 for FCU
- However FCU model shows:
 - ✓ For 55°C panel/ambient temp. (qualif. level)
 - ✓ Δt PSU = 6°C
 - Maximum box temp. = 65°C
 - Maximum board (мси/мас) temp. = 78°С
 - Too close to derating rules (85°C for part case & 110°C for junction)
 - To conservative estimation to be refined









Interfaces with S/C

• Allocated Budgets are almost meet:

SIZE	DCU	Design:	490x285x305 (mm)	
		IID-B:	494x289x3	05
	FCU	Design:	370x325x3	36 (mm)
		IID-B:	370x325x3	36
MASS	DCU	Design:	15.67 kg	
		IID-B:	15.50 kg	
	FCU	Design:	15.28 kg	
		IID-B:	15.00 kg	
DISSIPATION	DCU	Design:	33.2 W	
		IID-B:	37 W	
	FCU	Design:	47.6 W	80.8 W
•		IID-B:	42.9 W	79.9 W



of march)

DRCU Design



EEE parts

• Specification

SPIRE

- A DCL for DCU and SCU (CEA)
 - ATP for LLI 01/03/02
 - ATP for QM(2) 31/01/03
 - ATP for FM active parts 03/02/03
 - ATP for FM connectors 31/01/03
 - ATP for passive parts pending
- A DCL for MCU (LAM)

• Procurement

- All parts are procured through the First/Planck Parts Procurement System
- Except one self-procured: operational amplifier (ref.OP400)
 - Specific packaging for cost reduction and size optimization
 - Procurement of dices (3000) from Analog Device
 - Wafer Lot Acceptance (MIL-STD-883), Packaging, Qualification test (ESA/SCC900 level B), Up-screening (ESA/SCC 9000 level B), LAT 2





Critical Points

- **PSU late availability:**
 - **Grounding scheme limits PSU injected current propagation**
 - Need to specify accurately performance at interface level
 - SU EM model delivered (temporally only) to perform capability tests with QM2 of DRCU
- Late test of the DRCU with CQM FPU:
 - **QM2** design starts before test result
 - **C** Risk of late modification of QM2
 - JPL test cryostat with a few bolometers available at CEA
- Board Operating temperature:
 - Operating temperature too close to allowed maximum
 - **Solution** Model to be refined: PSU Δt, P_{dissip}(board), ...







Warm Electronic DCU Design



FREDERIC PINSARD Service d'astrophysique CEA/DAPNIA pinsard@cea.fr





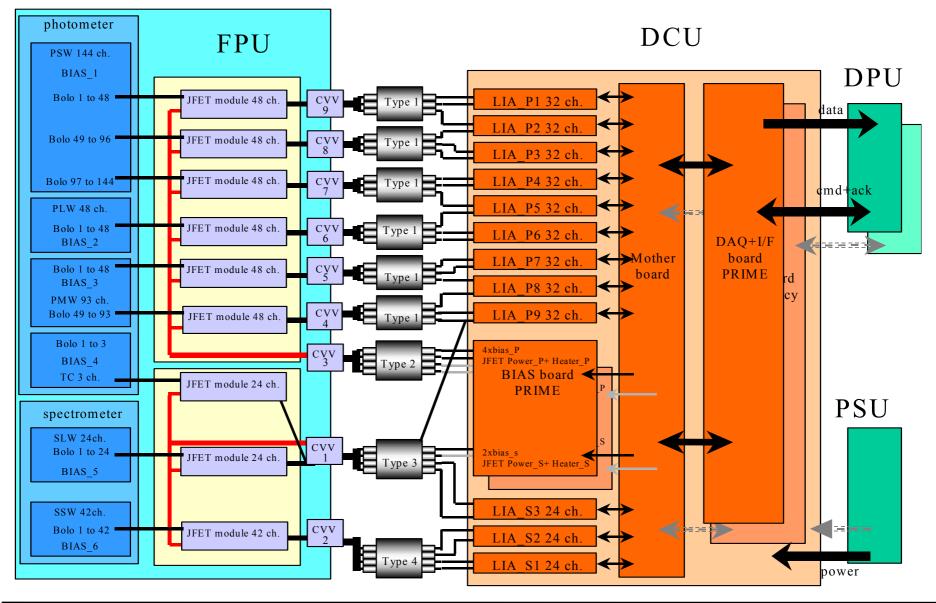
DCU Overview (1)

- The DCU is a one-box unit:
 - The Detector Control Unit comprises analog and digital electronics exclusively devoted to the bolometers' operation.
 - In this box, 16 boards are connected on a back-plane printed circuit board.
 - 9 LIA_P boards process the photometer analog signals.
 - 3 LIA_S boards process the spectrometer analog signals.
 - 2 BIAS boards (1 prime & 1 redundant) distribute the bolometers' bias and JFETs' supply.
 - 2 DAQ+IF boards (1 prime & 1 redundant) digitize the signals and receive /decode the commands.





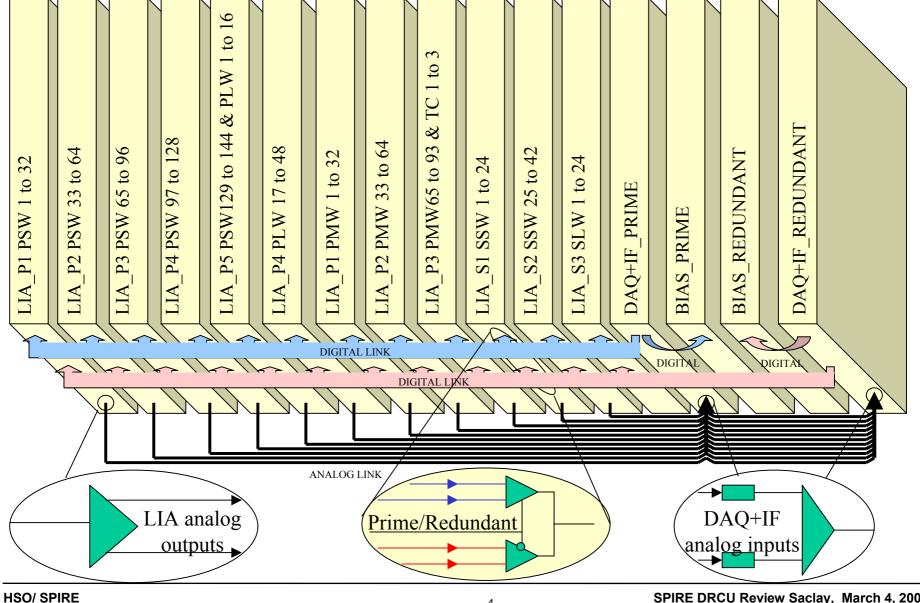
DCU Overview (2)







DCU internal connections



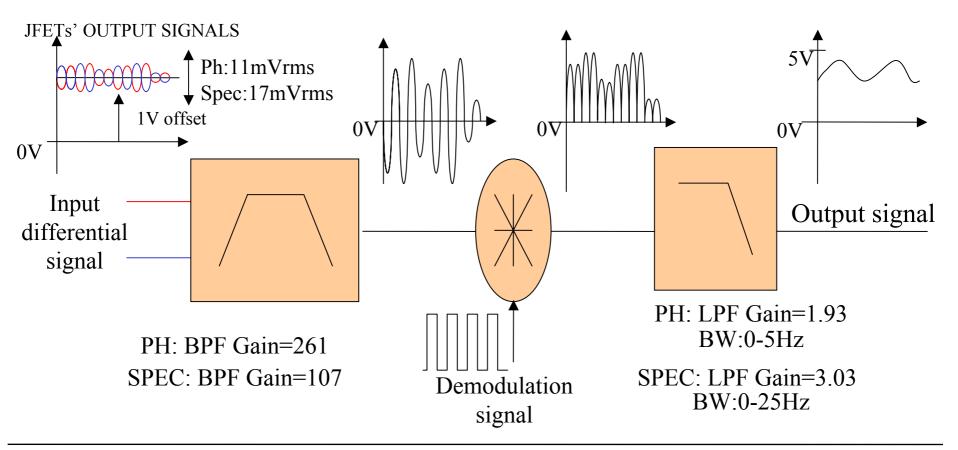


LIA (1)



•Analog processing channels:

- Functions: to receive, amplify, demodulate & filter the bolometers' signals
- Total number 354 : 288 for the photometer + 66 for the spectrometer









•QM1 measurement main results:

BPF	Photo	meter	Spectrometer		
DIT	min	max	min	max	
Gain	260	265	113.2	115.5	
F _{-3dB} low in Hz	34.4	35.1	35.2	35.9	
F _{-3dB} high in Hz	1453	1483	2673	2727	

Channel	Photo	meter	Spectrometer	
Channel	min	max	min	max
Gain	446	449	308	315
F _{-3dB} low in Hz	4.85	4.95	24.9	25.1
CMR	-85dB		-80dB	
Input noise in nVrms/√Hz		4.5		5.5

NOTE: 3 channels have flaws, but these problems are being investigated







• Bias generators:

- Functions: to generate sine biases for the bolometers and the DC biases for the JFETs and heaters
- Adjustable sine biases:
 - Photometer : 1sine generator with 4 independent channel amplitudes
 - Spectrometer : 1sine generator with 2 independent channel amplitudes
- Adjustable DC biases:
 - Photometer : 12 generators for the JFET + 1 for the heater with 7 buffers
 - Spectrometer : 3 generators for the JFET + 1 for the heater with 2 buffers

	Sine bias		DC bias		
	Ph/Spec	TC	Vss	Vdd	heater
Voltage range in Vrms	0 to 0.2	0 to 0.5	0 to -5	2.5	0 to -5V
Frequency range in Hz	40 to 305	40 to 305	DC	DC	DC
Output current max in mA			5mA	5mA	2.5mA/buffer
Noise in nVrms/√Hz	XX	XX	250	200	250







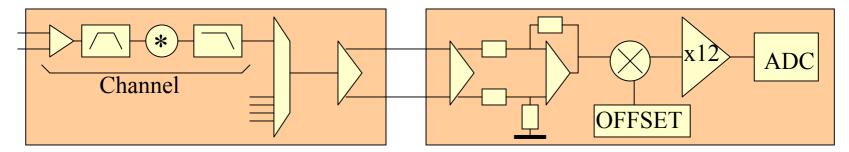
- DAQ+IF functions:
 - Digitized data and transfer, timing cycle, command decoding, hk parameter transfer.

	Number	Parameter values	Range
BIAS frequencies	2	40 to1FF	40 to 305Hz
Sample frequencies	2	3 to FF	$F_{BIAS}/3$ to $F_{BIAS}/256$
Demodulation phases shifts	6	0 to FF	0 to 360°
Offsets	354	0 to F	0 to 5V
Data transfer frequency	-	-	2.5Mb/s
HK& command transfer frequency	-	-	3125kb/s
Data ADC	6	-	-2.5 to 2.5V (16 bits)
Photometer picture acquisition	-	-	6ms
Spectrometer picture acquisition	-	-	1.2ms
Frame number	1	0 to FF	1 to 255 or continue





NOISE



Last gain stage on DAQ+IF (FUNC-02-7) Vrms	2,51E-06
Offset stage on DAQ+IF (FUNC-02-06) Vrms	2,68E-06
Substractor stage on DAQ+IF (Analog receiver) Vrms	2,43E-06
Differential receiver stage on DAQ+IF (Analog receiver) Vrms	2,15E-06
Differential transmitter stage on LIA Vrms	2,87E-06
LIA photometer channel (FUNC-02-05,*-04,*-03,-02,*-01) Vrms	3,70E-06
LIA spectrometer channel (FUNC-02-05,*-04,*-03,-02,*-01) Vrms	6,13E-06
ADC (DCU-FUNC-03) Vrms	5,80E-05
Photometer input noise V/VHz	8,20E-09
Spectrometer input noise V/ \sqrt{Hz}	6,57E-09



STATUS



- The DCU QM1 in progress
 - Manufacturing and assembly of the LIA_P2, LIA_S2 and LIA_S3
 - Total noise measurement with the OP484 on DAQ+IF board
- The DCU QM1 future
 - Test of the new LIA boards
 - QM1 assembling
 - QM1 testing alone
 - Testing of the DCU QM1 with the test cryostat from JPL
 - Testing of the DCU QM1 with simulators

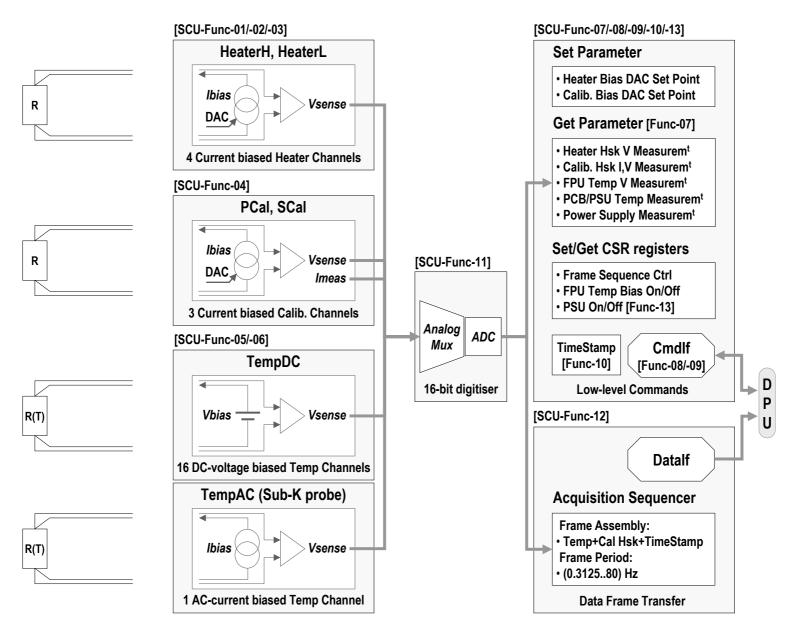
— · · ·

The SCU

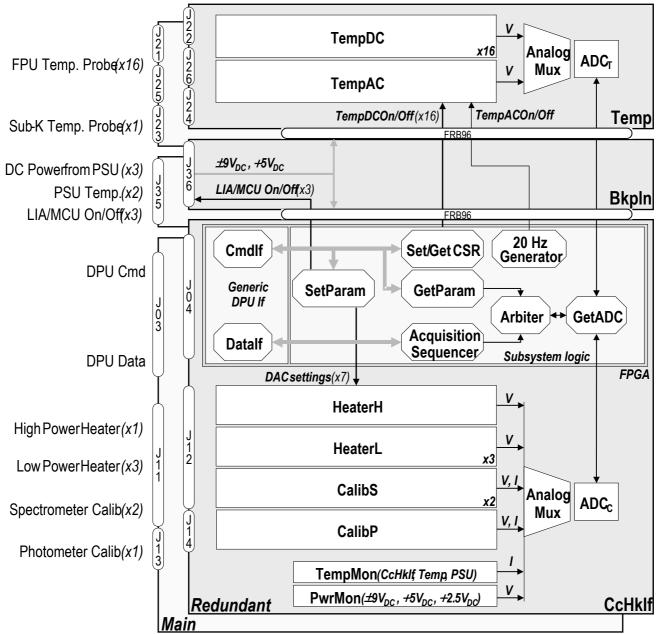
Functions Architecture DPU Interface Subsystem logic Analogue channels Boards Test strategy Status

Michel MUR (CEA/DSMDAPNIA, 01 69 08 14 67, michel.mur@cea.fr)

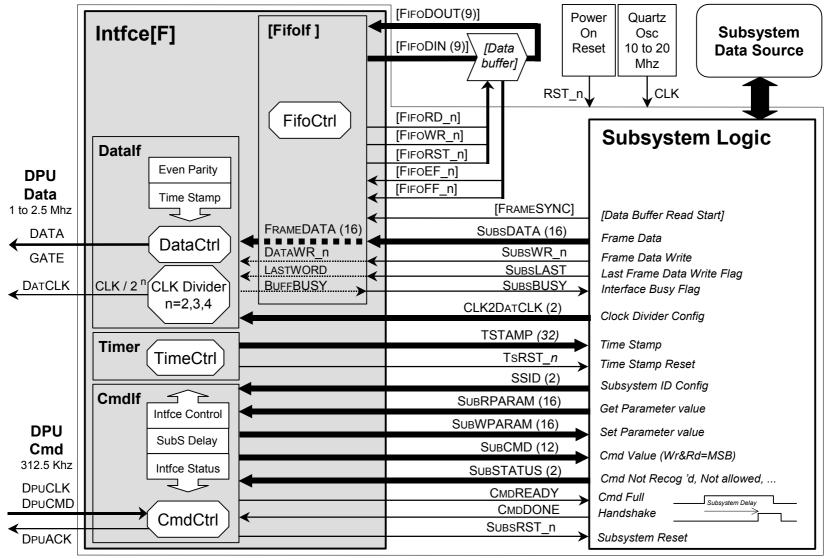
Functional overview



Architecture



Generic subsystem interface: concept



FPGA circuit

[...] is set for optional FIFO Implementation

Generic subsystem interface: functions

Intfce

- o Virtual component
- VHDL RTL for synthesis (ACTEL RT54SX32-S FPGA target)

Cmdlf

- Runs with DPU 312.5 kHz Clk alone
- Deserialises Cmds, serialises Ack
- Filters local/subsystem commands
- Supports simple, asynchronous handshake dialogue with subsystem
- Handles subsystem handshake timeout

Timer

o Maintains Time Stamp

Datalf

- O Runs from local oscillator
- Supports [1.. 2.5] MHz data rate
- Simple, synchronous subsystem word-based data interface
- Appends Time Stamp and parity to subsystem data
- O Optional First In First Out subsystem buffer
 - Synchronised by subsystem for frame transmission (Frame Sync)

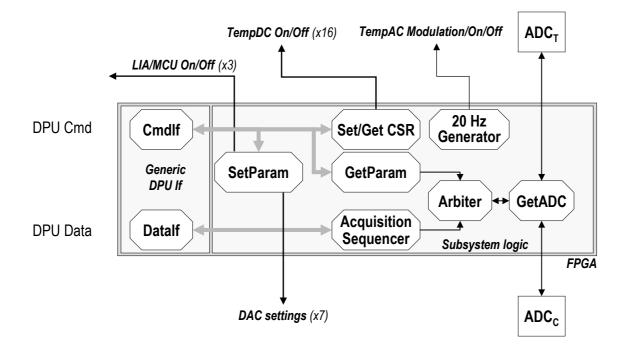
SCU subsystem logic

• Parameter access

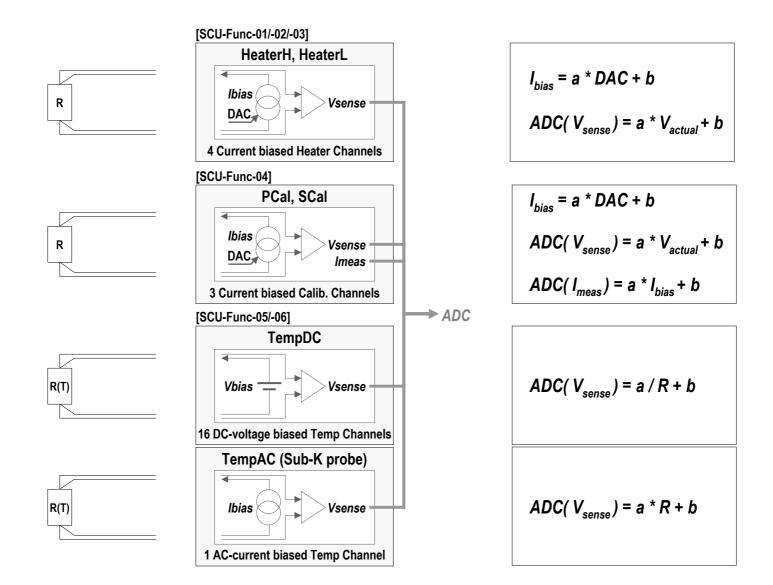
• Access to all parameters through Cmd interface (GetParameter)

o Data frame sequence

- 0 (infinite),1 .. 31 frames per sequence
- O 0.3125 .. 80 Hz frame frequency
- Word-per-word transmission (no frame buffer)
- Maximum analogue parameter collection interval: less than 6 ms
- Pseudo-random test pattern capability

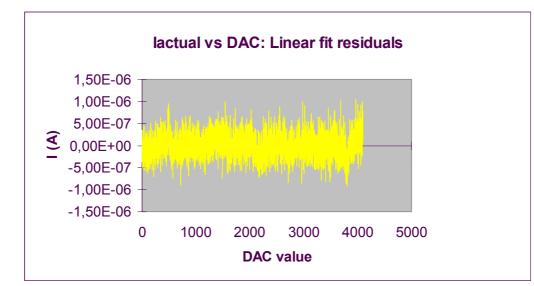


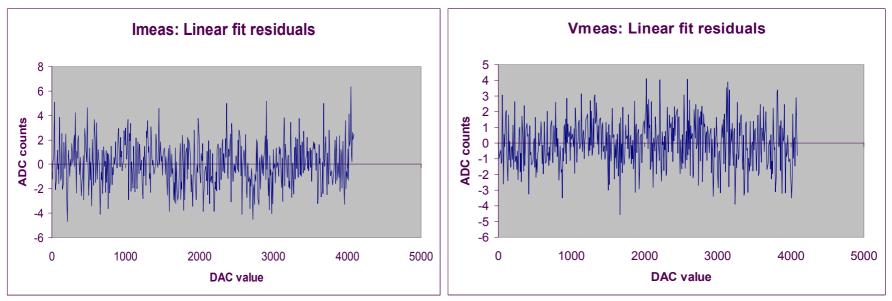
Analogue measurements



Calibrator prototype: Linearity

o Linearity test at 25°C



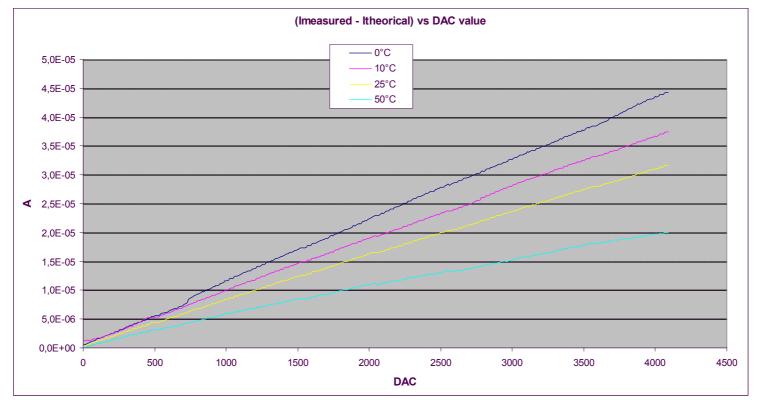


M. Mur, DRCU DDR review, 04 mar 2003

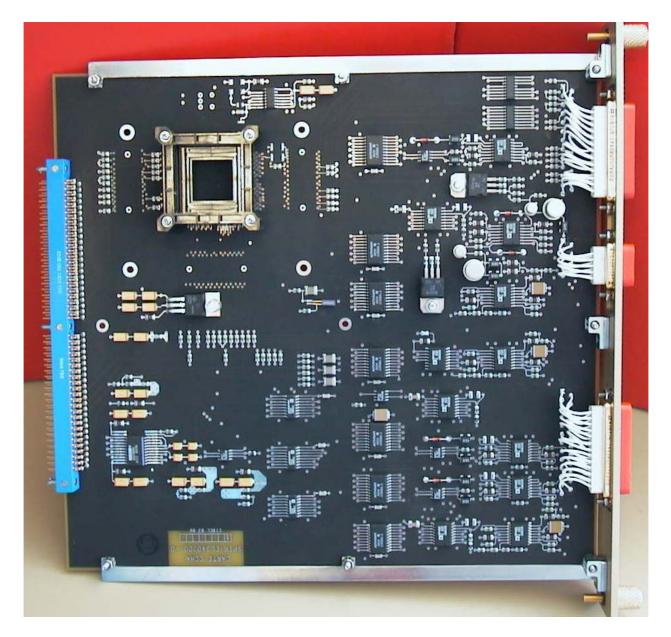
Calibrator prototype: Stability

Variation with temperature

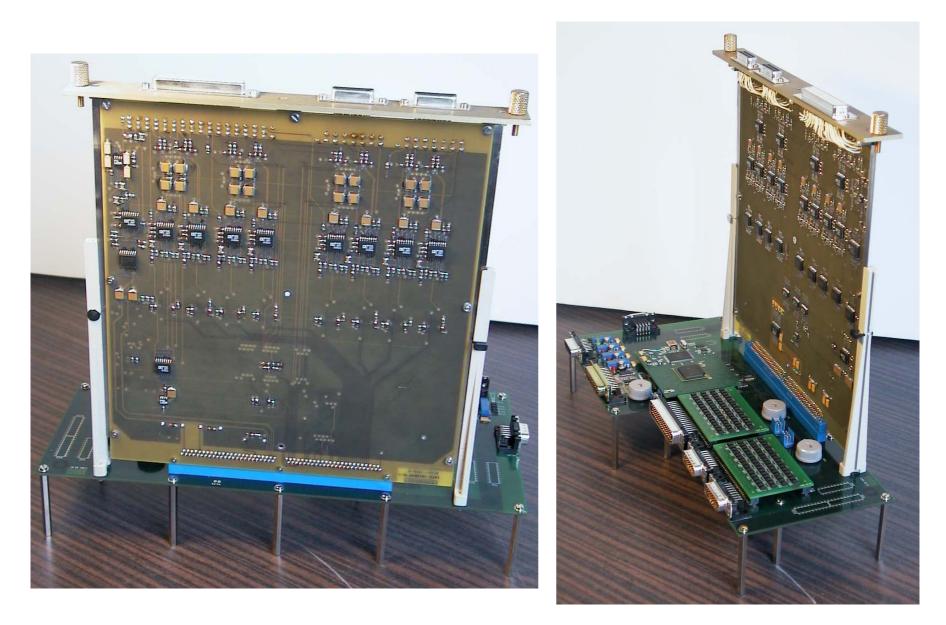
- 4% of the stability budget
- Prototype current variation: 25uA/50°C@9mA
- \circ corresponding relative dependence: < 60 ppm/°C.
- Specification for relative stability: $< 5.E^{-3}/h$ (maximum temperature drift: 3K/h).
- Without correction: <4% of the total stability budget
 - (180 ppm of the requested 5000 ppm/h).



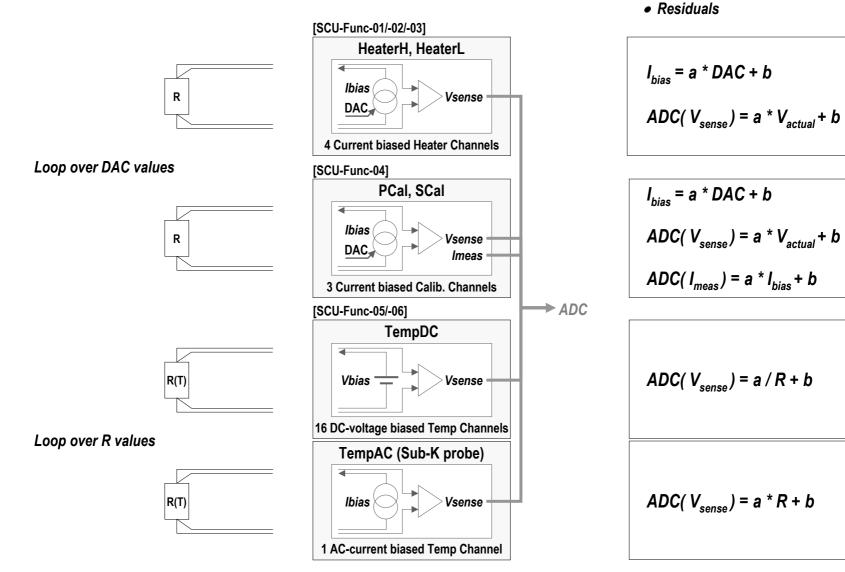
Boards: Cchklf



Boards: Temp



Test : measurements



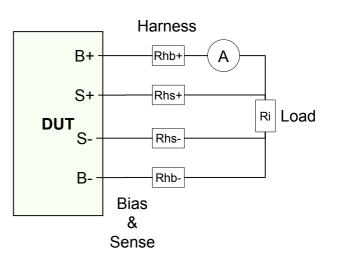
Linear regressions: Measure

Slope (a)Intercept (b)

Test : principle

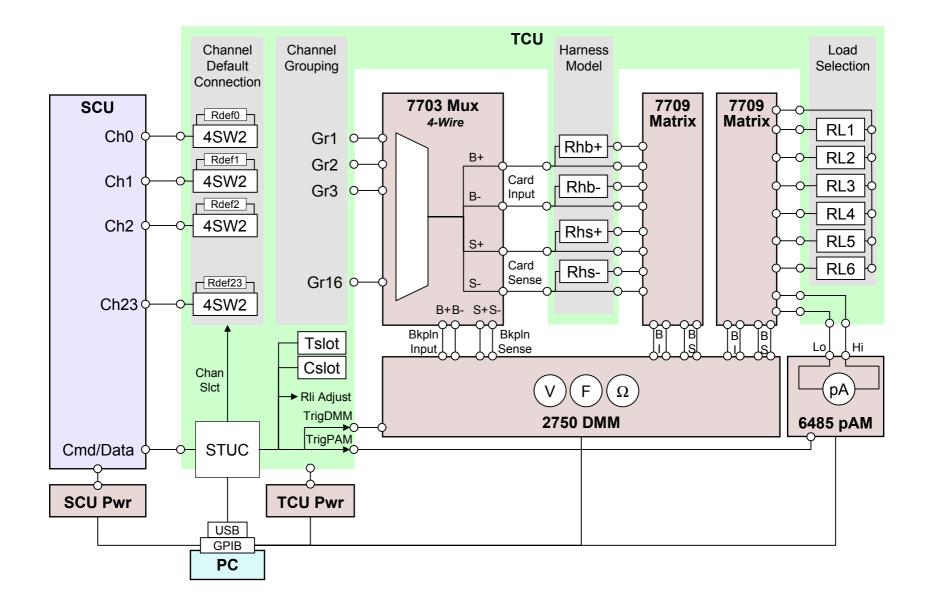
Generic circuit (all channels)

- Variable load for calibration of a 4-wire measurement circuit
- Possibility to insert/bypass Rh resistors (to model the harness resistance)
- Possibility to select one out of several reference loads Ri Ο
- Path to measure current in a separate ammeter



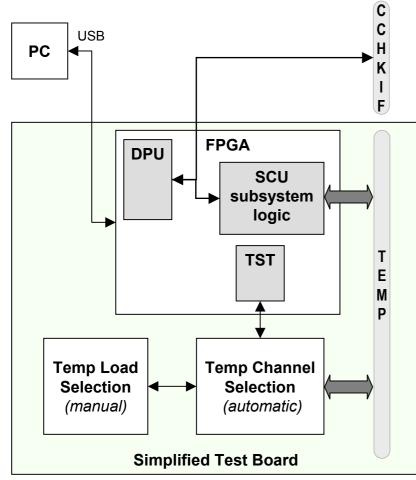
Matrix connections А Test board B+ Rhb+ Rhs-S-Rhb B-Rhs+ S+ 3 5 7 8 4 6 1 2 4 5 7 8 Example Rhb+, Rhb- inserted Ο 2 ۱a 12 15 16 Rhs+ inserted \mathbf{O} R4 R3 R2 R1 3 17 18 10 23 20 22 24 Rhs- inserted Ο R4 load selected Ο 4 25 26 27 28 31 29 30 32 5 33 34 35 39 36 37 38 40 6 4

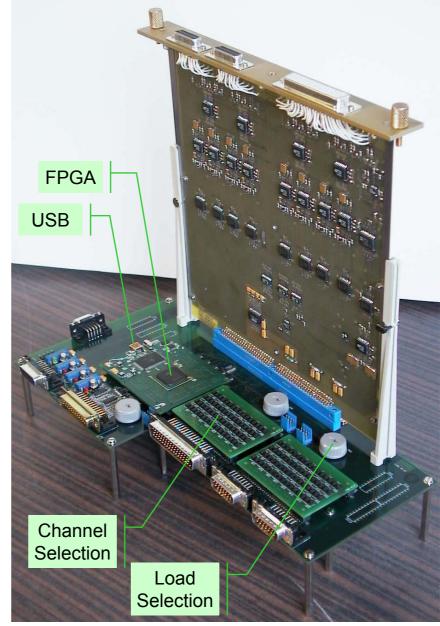
QM2/FM Test : Automated setup



QM1 Test : Simplified setup

- Direct test of Temp board
 - O DPU host interface in FPGA
 - Nominal Subsystem logic in FPGA
- o External Test of CchkIF
 - o fixed loads





Status (QM1)

Board design

o Completed

• FPGA design, simulation, Place & Route validation (Actel)

o Completed

Test preparation

- Hardware (Simplified Test Board)
 - ♦ Ready
- o Software
 - Primitives (Host commands)
 - Completed
 - Application (measurement loops)
 - In progress
 - Measurement analysis (simple linear regression analysis)
 - « Manual » process for QM1

• Test activity & report

o March-April 2003

Mechanisms Control Unit

D. Pouliquen

Laboratoire d'Astrophysique de Marseille

MCU

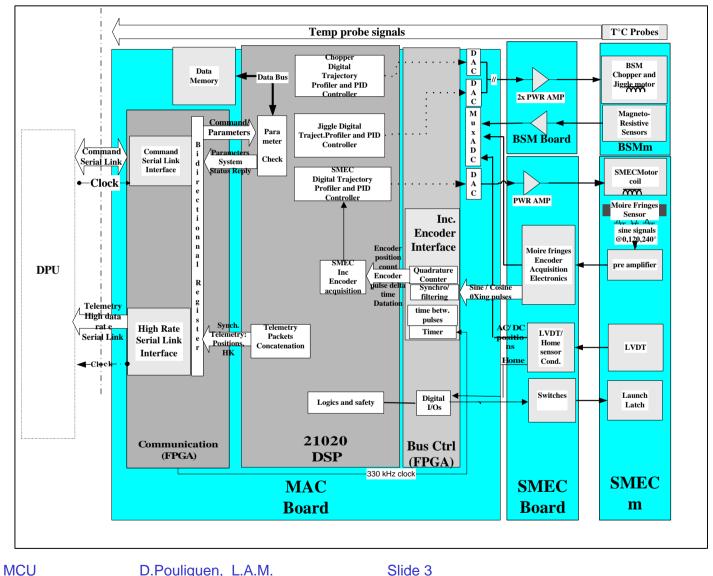
The MCU controls the SMEC and the BSM mechanisms.

The MCU is designed and developed at LAM with the cooperation of UKATC for the BSM part and of CEA-Sap for the DRCU part.

- Based on a DSP 21020, with assembly language software
- Controls 3 axis : 1 for SMECm and 2 for BSM
- The MCU comprises 6 boards mounted in the FCU:
- 2 Multi Axis Controller boards (nom+red)
- 2 Spectrometer MEChanism board (nom + red)
- 1 Beam Steering Mirror board (nom+red on the same board)
- 1 backplane board.

MCU : short description (1/3)

- DSP 21020 + mechanism control software
- Interfaces with DPU = one FPGA for both the TM and the TC.
- One analogue board per mechanism to condition the signals to and from the mechanisms (position signals, actuator currents)



MCU : short description (2/3)

SMECm Optical Encoder Position Acquisition

Calculated on the basis of the 3 sine optical encoder signals after pre-amplification, conditioning to be read directly by the DSP via a multiplexed 16 bits ADC for arctangent calculation.

SMECm Optical encoder LED control

Because of the possible decay of flux emitted by the optical encoder LED due to ageing, 8 possible current levels can be set by the MAC board through the digital I/O port (3bits encoding).

SMECm Degraded mode control using the LVDT

For R=100 travel (+/- 3.2 mm)

signals acquisition is done on the SMEC Board and digitised by a 16 bits multiplexed ADC converter

useful range of the LVDT measurement with nominal linearity = +/-2.54mm extended at twice this length with poorer linearity performance.

SMECm Degraded mode control using the motor back emf

For a complete SMEC mechanism travel

Uses the mechanism stiffness law

permits a velocity control of the mechanism only.

MCU : short description (3/3)

BSM Position = measured by magneto resistive signals

BSM Movement = angular travel in two orthogonal axes. Performed with actuators

BSM Control =

- digital conventional PID (3-term) controller with corrections for cross-coupling between axes- in the MAC Board.
- Each axis can move independently. Typically, a step command waveform is assumed, and above a certain amplitude (10% of peak), it is profiled to produce a sinusoidal acceleration demand.
- The movement with respect to time is profiled via stored parameters to give a minimum energy, minimum noise position change, particularly for step commands. In general the movements are repetitions of the same position/time profile.
- In addition, in the event of measured behaviour resulting in a fault diagnosis, some system backup procedures are available. Diagnosis of excessive position errors and analysis of recorded transient behaviour during operation can result in modifications to the control system by uploading different parameters.

MCU : Design change since MCU DDR (Oct 2001) [1/3]

> Addition of boards temperature measurements

One temperature sensor added on each nom and red card Total = 6 sensors (no sensor on the backplane)

Method of SMEC mechanism speed control with the optical encoder revised:

the optical encoder zero crossing counting is done exclusively by software. It was previously done by hardware.

- => suppresses offsets adjustments in the hardware
- => simplifies the hardware
- => simplifies the control software
- ECR issued and accepted

Modification being implemented

MCU : Design change since MCU DDR (Oct 2001) [2/3]

> Damping of the SMEC mechanism

One relay added that short circuits the coils when no power available

When one coil in use, the other one remains short circuited

Provides damping to improve the mechanism control

Prevents the mechanism from banging against the mechanical stop in case of sudden power failure

Suppression of the BSM launch latch

due to successful vibration tests of the BSM without launch latch => simplifies the BSM board

=> erases a problem with the SPIRE harness

MCU : Design change since MCU DDR (Oct 2001) [3/3]

Introduction of a BSM damping for launch

The need is not clear. Complement of study under progress at UKATC.

> Introduction of a BSM damping for control

Control easier with little dampening => introduction of a resistance in the actuators coils circuit. Done on the QM1, perhaps suppressed on further models.

Decisions concerning the BSM to be taken this week with UKATC and SPIRE system team

CEA-SAp

MCU : Interfaces documents

- > DRCU ICD Sap-SPIRE-CCa-075-02 Issue 1.0, 14 Feb 2003
 - => MCU / DPU, MCU / PSU and MCU / Mechanisms electrical interfaces => MCU command list
- SPIRE Harness Definition Document, SPIRE-RAL-PRJ-000608 Issue 1.1, 8 July 2002
 - => Mechanisms simulator electrical interfaces (pin out = mechanisms connectors pin out, Sub D connectors)
- > SPIRE FCU MICD, SPIR-MX-5200-000 Issue E, 26 Sep 2002

=> MCU Connectors position, reference axis, etc...

- SPIRE Rack type LIA Plan d'interface, SPIR-MX-5110-000 Issue A, Oct 2001
 - => MCU boards mechanical interfaces

MCU : the models [1/2]

> QM0 : for communication tests

- Built at LAM
- New model introduced for planning reasons
- Form & fit, electrical, command interface & flight functions Ok
- ALTERA FPGA including CEA DAPNIA Communication VHDL issue 0.4
- Commercial components, no redundancy
- Not suitable for mechanisms control
- Delivered with mechanisms simulator and cables

> QM1 : for CQM tests

- Built at LAM
- Same as QM0 plus mechanism control capability
- To replace the QM0 in the FCU QM1

After QM1 delivery, the QM0 comes back to LAM and can be refurbished at QM1 level.

MCU : the models [2/2]

> QM2 : Used to qualify the electronics

- Sub contracted by LAM
- QM2 design = QM1 design
- Form & fit, electrical, command interface & flight functions Ok
- Military components, redundancy
- ACTEL FPGA including CEA FPGA Communication VHDL (black box) issue TBD
- Delivered with mechanisms simulator and cables

QM2 to be used with FPU FM as FCU FM not available on time

FM and FS

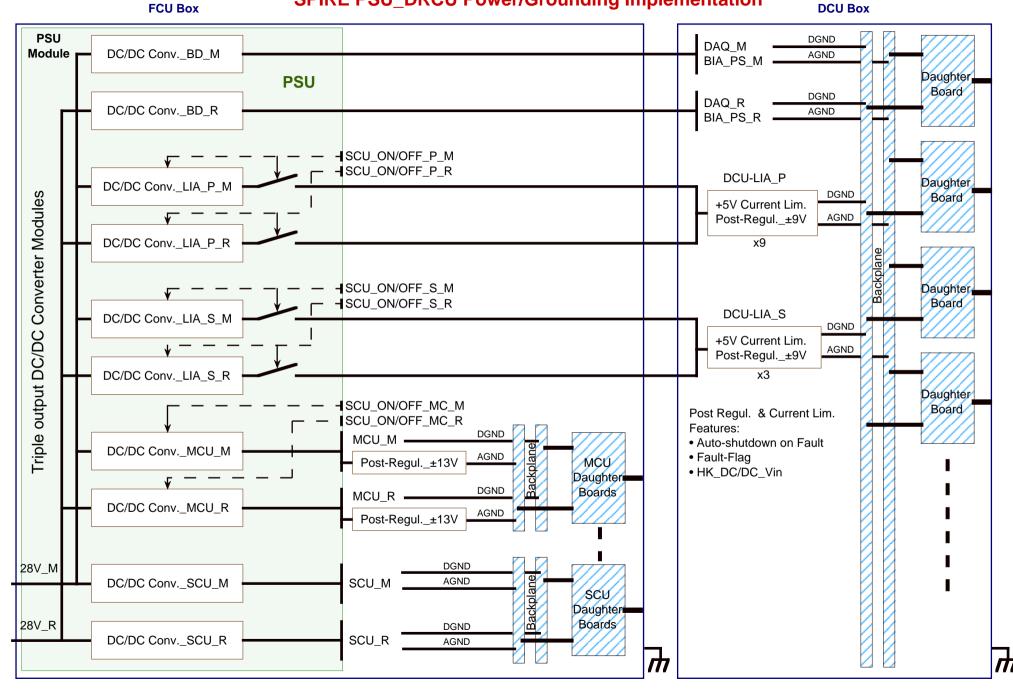
- Complete flight models
- Sub contracted by LAM (same contract and contractor as for the QM2)

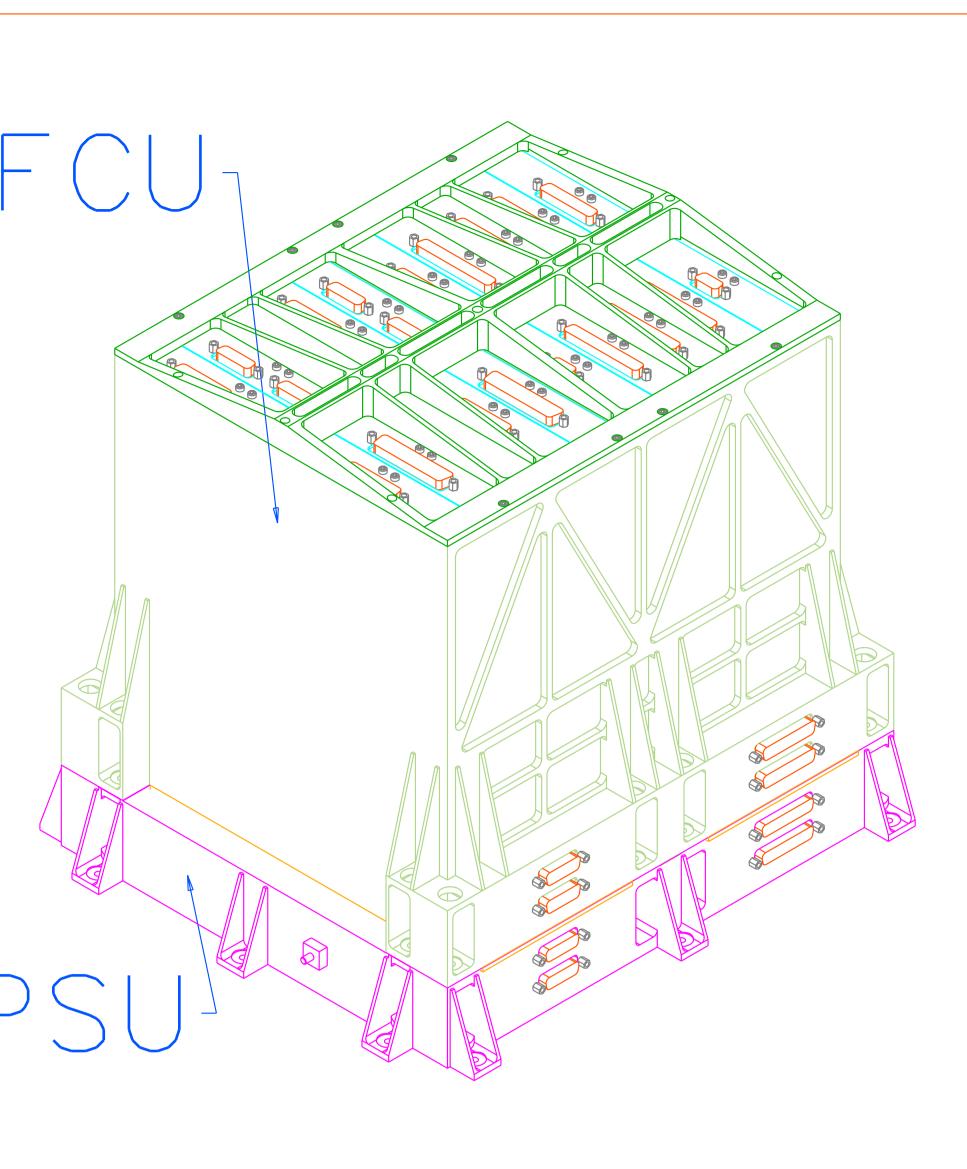
All MCU models to be delivered by LAM to CEA

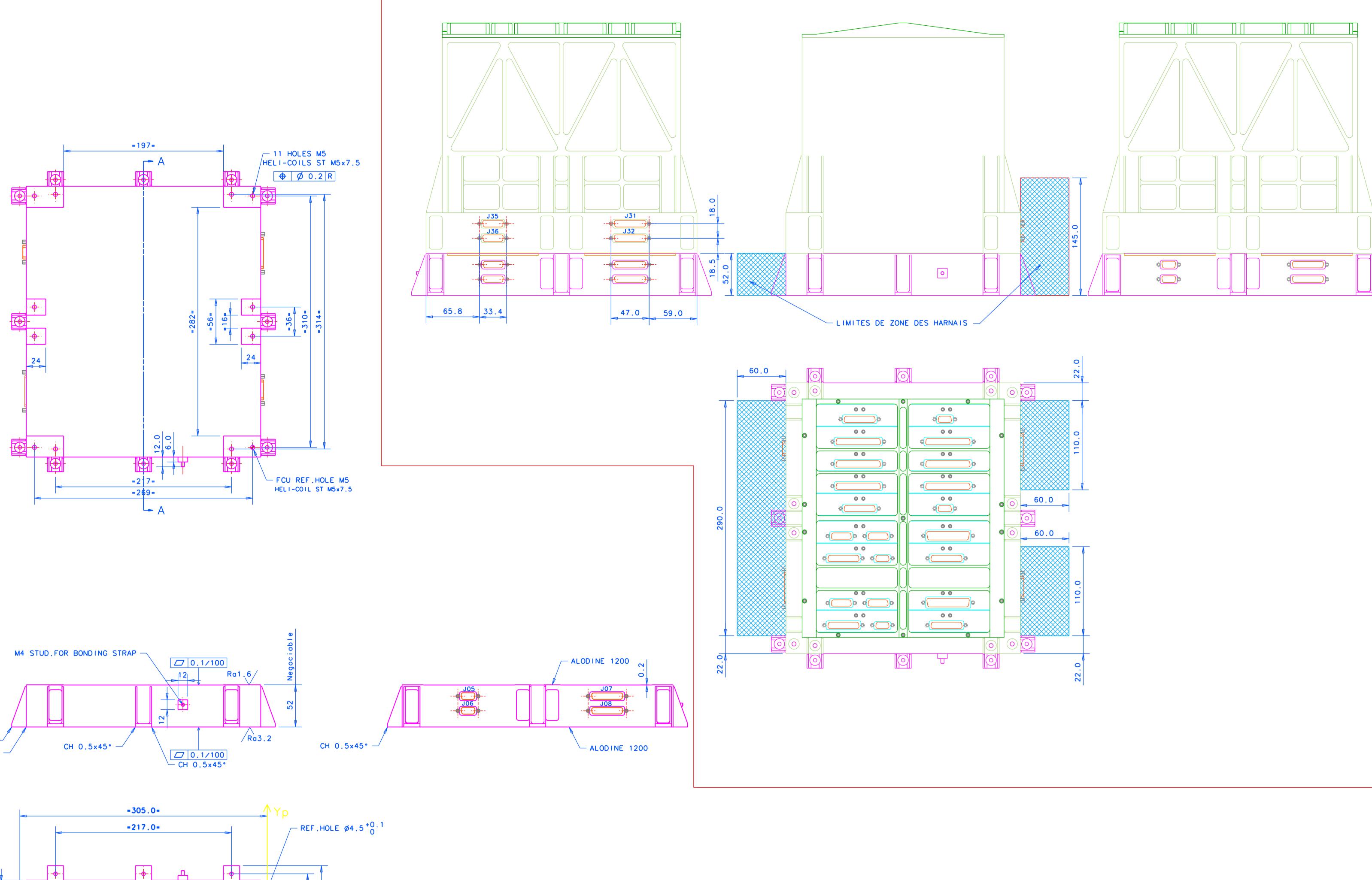
SPIRE PSU DRCU Power/Grounding Implementation

DCU Box

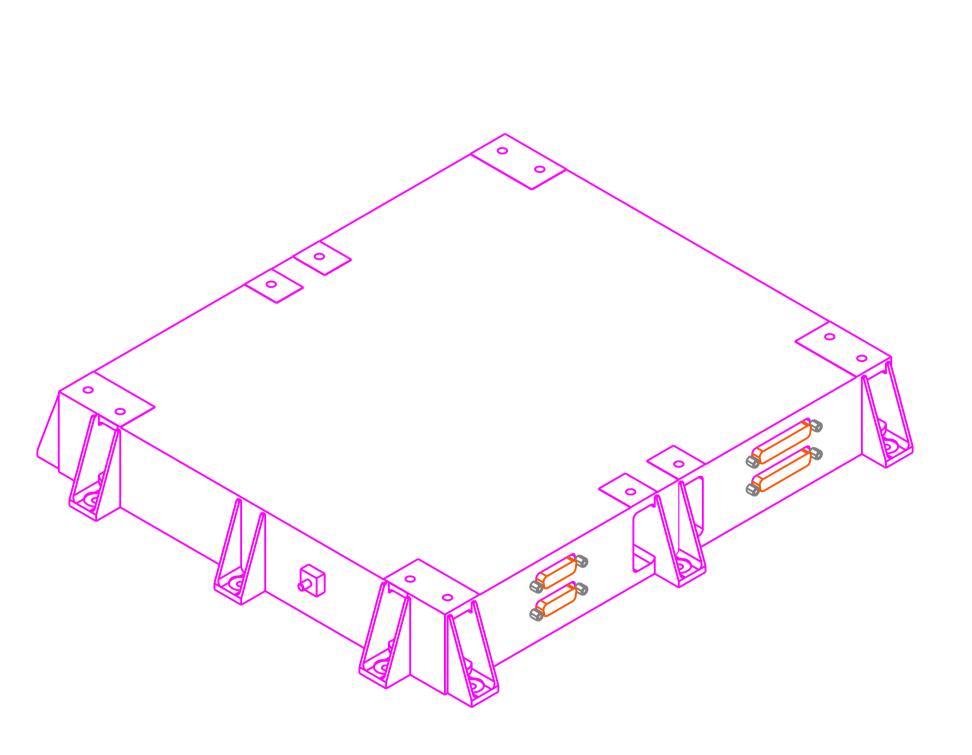
DS-20/06/02

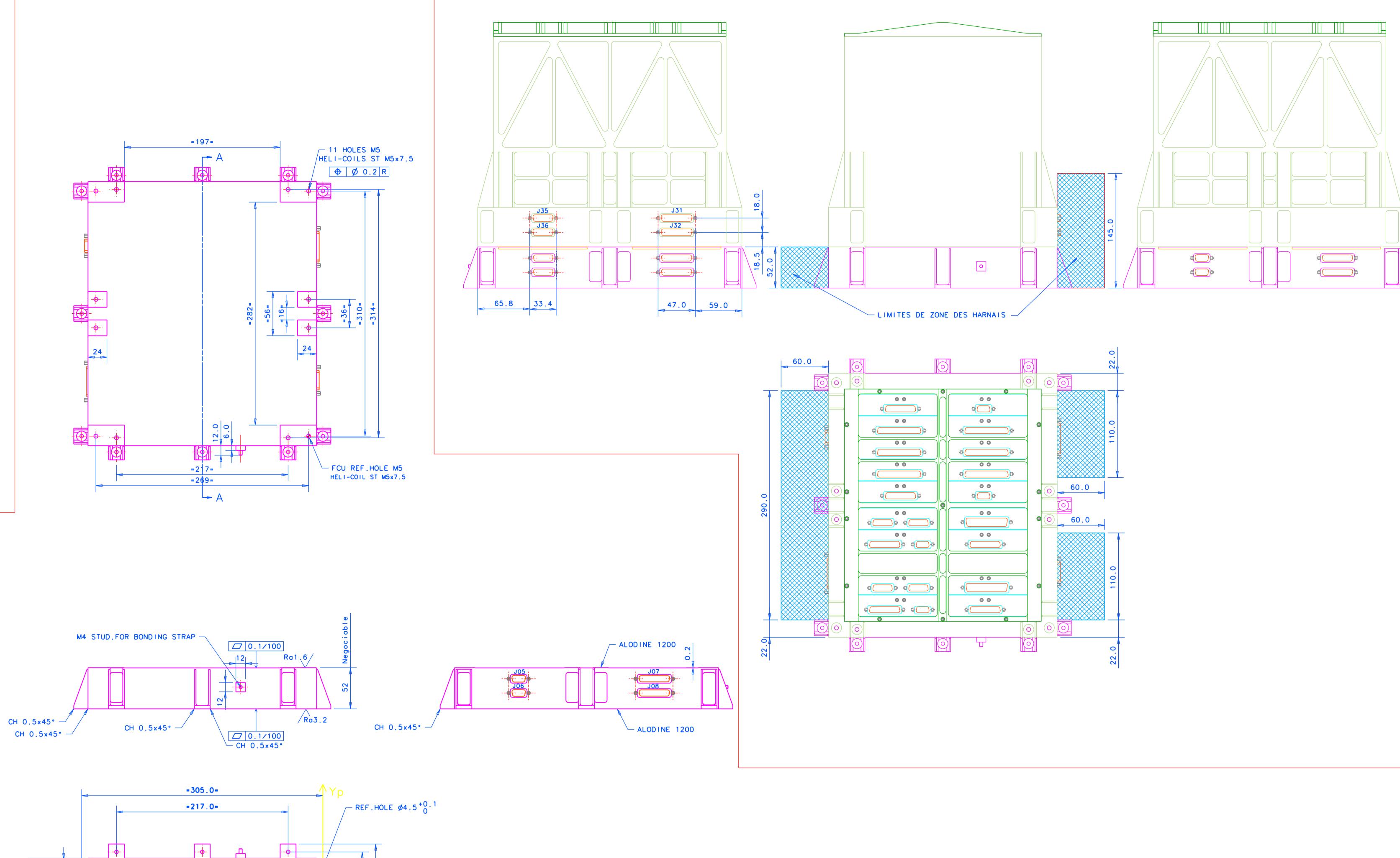


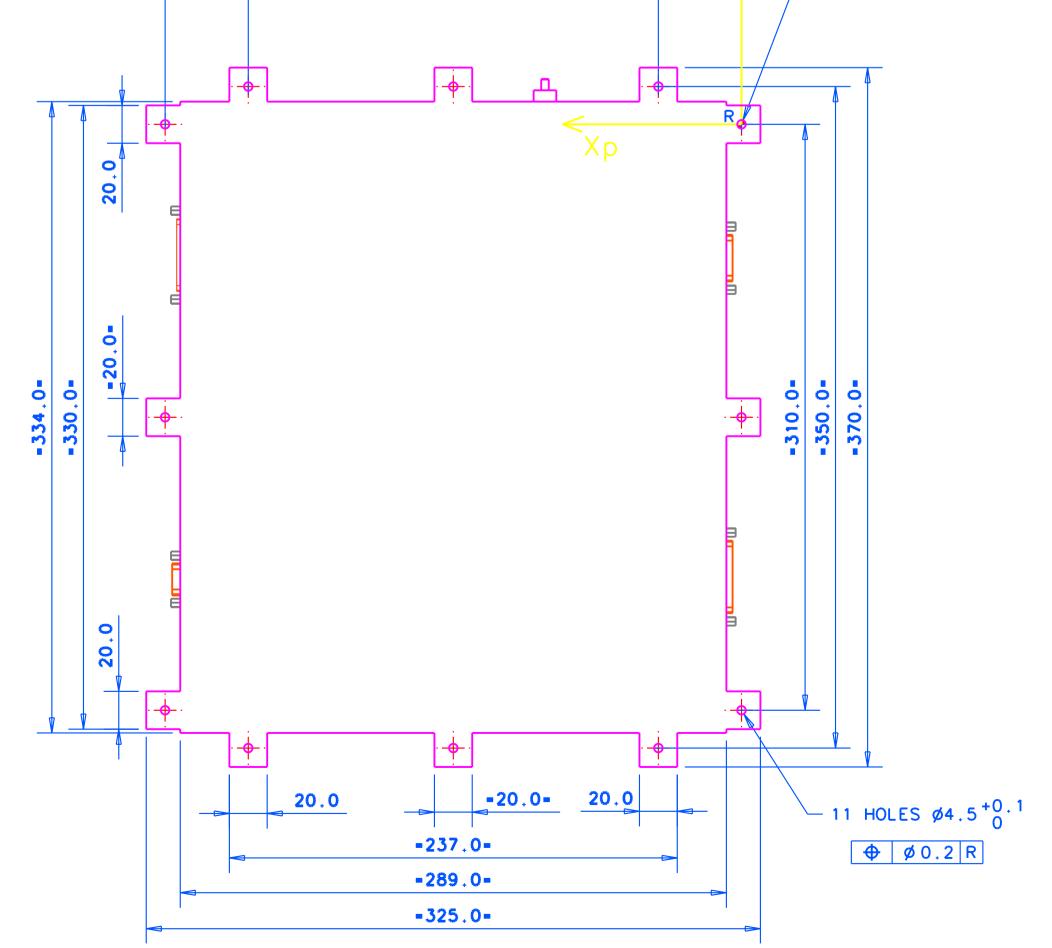


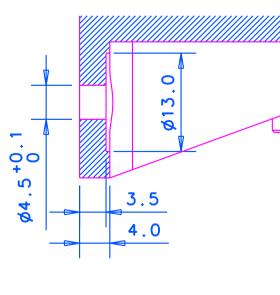


_____) _____









COUPE PARTIELLE A-A ECH:2

CONNECTOR	TYPE P
° 1	
CONNECTOR	TYPE S
	1 •

CONNECTORS					
IDENT	TYPE	FUNCTION			
J05	DEMA 9P	PSU-M/PCDU-M			
J06	DEMA 9P	PSU-R/PCDU/R			
J07	DBMA 25S	PSU-M/DCU			
J08	DBMA 25S	PSU-R/DCU			
J09	DBMA 25S	PSU-M/MCU-M			
J10	DBMA 25S	PSU-R/MCU-R			
J33	DAMA 15S	PSU-M/SCU-M			
J34	DAMA 15S	PSU-R/SCU-R			

			s 09/02	20504.00	1	1
B	Mise à jour connecteurs					
A	Origine		07/02 Date			
indice				Dessiné par	Vérifié par	Approu
	ifications part	icuiteres				
nces les	Indi	ce de rug	osité gé	néral XXX	X SOUS-	TRAI
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t o l gér	🗢 🔶 🦣 🚛 Cass	er les ar	igles vif	S		
Matië	ère:		Pro	otection		
Trait	tement thermiqu	e :		nelle Poi 72	ds Nivea	u qua
PSU ME(IRE HSFC J BOX CHANICAL	INTER				
	SAP/GERES	COMMISSAI L'ENERGII	RIAT A			N SA
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HERSCHEL—SPIRE

FCU-PSU

Model policy:

STM

- Will contribute to the qualification of the FCU box
- Secondary Power supplied by an external power bench

EM

- Not a deliverable item
- Compliant Mechanical and Electrical I/F
- Will be used by the contractor for verification purposes, test of corrective actions...
- Will be borrowed for electrical compatibility test at Saclay

FΜ

• Flight compliant

Spare

- PCB or part level
- FM repaired and tested at acceptance level within 3 weeks

Expected Schedule:

- ITT in progress, first answers by the end of March
- Market rules completion and kick-off by the end of June (CEA-CCM calendar)
- FM delivery: kick-off + 14 months

CEA-DS-04/03/03



AIV DRCU TEST PLAN

- **OBJECTIVES** (as defined in the development plan)
 - To check Sub systems <u>Performances</u> and <u>Functions</u> at the appropriate level before integration into the instrument,
 - To perform <u>Qualification</u> or <u>Acceptance</u> tests of all individual Sub-systems before integration into the instrument.

• MAIN STEPS

To fulfil the objectives, the AIV plan defines :

- the actions to be performed for each model following the model philosophy (STM, QM1, QM2 and FM),

- the sequencing of the actions performed on units for each model (Flow Charts),
- the detail of each AIV action together with the resources required (SADT diagrams),
- the kind of tests performed on each unit / sub unit to ensure test coherency (Test matrixes),
- the test equipments required for each test (harnesses, LTU, FPU, PB ...),
- the documentation (test plans, logbooks, NCR ...),

Henri TRIOU SPIRE AIV March 4th. 2003



Classification of AIV actions

The AIV Actions consist in :

Inspections (concerns items delivered by subcontractor) that involves :

Incoming inspections :

- Visual inspection to verify:
- Marking of the box and of the connectors, checking of the connector itself,
- Mechanical integrity of the box,
- Surface treatment status of the box,
- Review of the delivered documentation,

Incoming tests :

- Simplified functional tests.

Assembly that involves :

- Visual inspection,
- Electrical interface verification to check the compatibility (electrical mass, Back Plane isolation ...),
- Mechanical assembly, Electrical tests,
- Simplified Functional tests

Integration of units that involves :

- Visual inspection,
- Electrical interface verification to check the compatibility of units
- Electrical tests

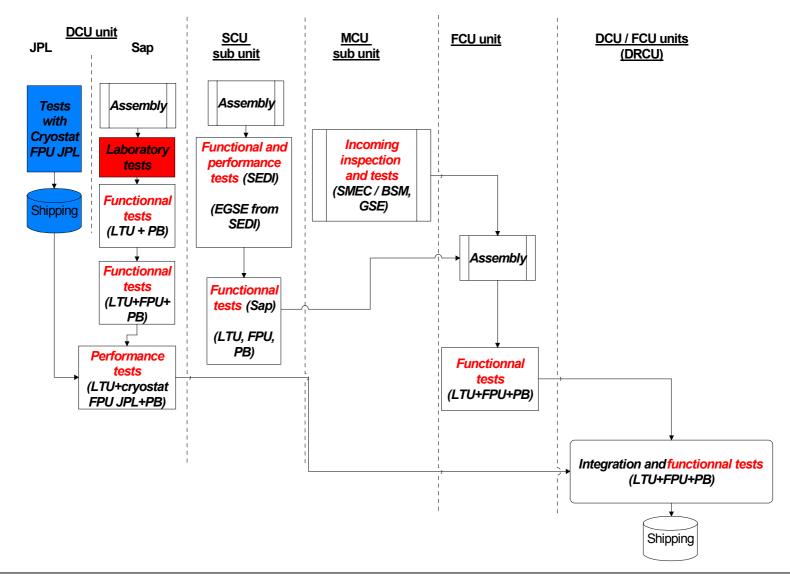
Functional / Performance tests following the system and interface requirements

Qualification / Acceptance tests performed under environment conditions following the system and interface requirements

= > We then detail the AIV action flow charts for QM1, QM2 and FM models



DRCU QM1 model flow chart (QM1 = test mean for CQM)

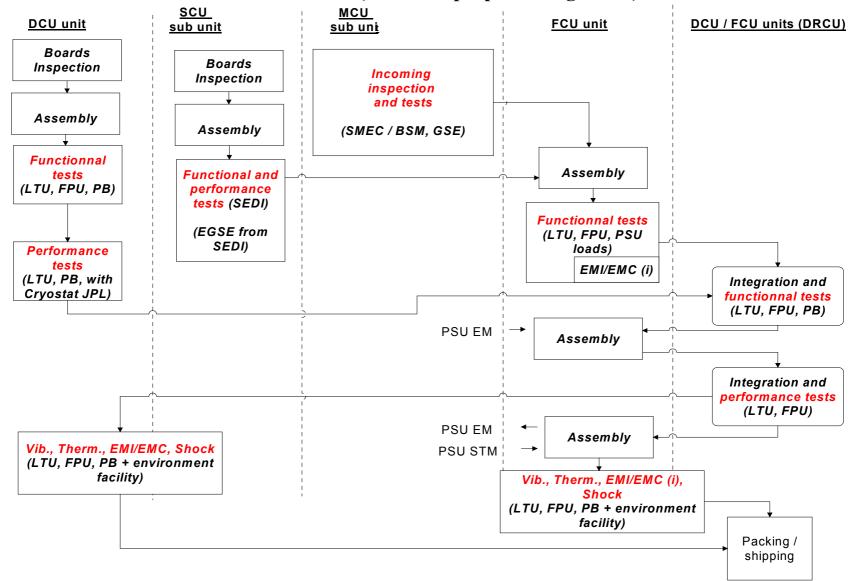


SPIRE DRCU REVIEW

March, 4th. 2003

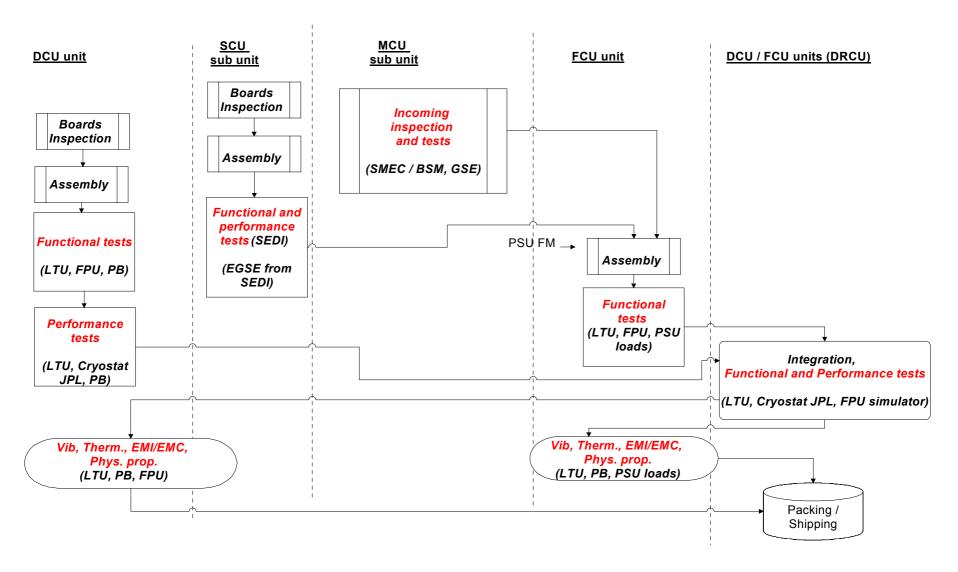


DRCU QM2 model flow chart (QM2 : to prepare integration)





DRCU FM model flow chart (For Acceptance tests)



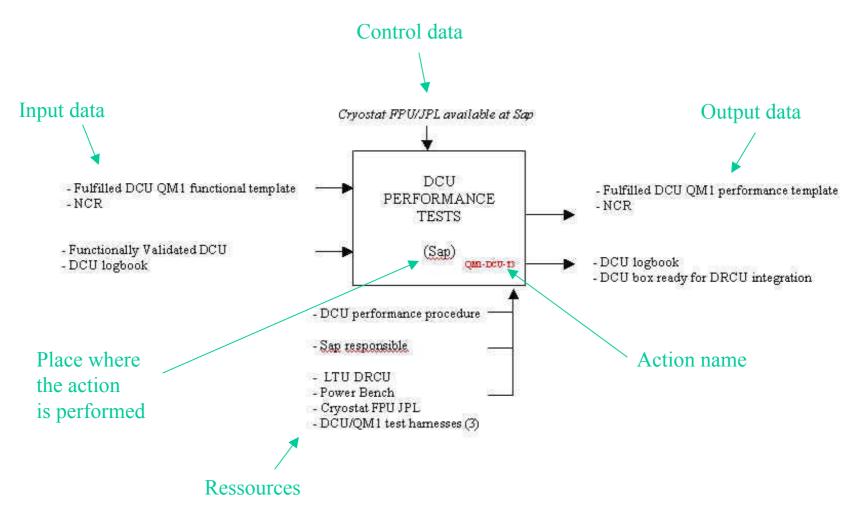
SPIRE DRCU REVIEW

March, 4th. 2003





SADT diagrams



SPIRE DRCU REVIEW

March, 4th. 2003

CONDSM-DAPNIA SAP

Unit test matrix (DCU or FCU)

Test / Model	QM1	QM2	FM
Inspection	A	Α	A ⁽³⁾
Electrical tests	Т	Т	T ⁽³⁾
Functional tests	T	Т	T ⁽³⁾
Performance tests	No Test	No Test	No Test
Vibration tests ^(*) Qualification level	No Test	T ⁽²⁾	
Acceptance level		6-3855	T ⁽³⁾
Thermal balance tests	No Test	No Test	No Test
Thermal tests (*)	No Test	1	
Qualification level		$T_{V}^{(2)}$	
Acceptance level			$T_{V}^{(3)}$
EMI/EMC tests (*)	No Test		
Qualification level		T ⁽⁰⁾	
Acceptance level			T ⁽³⁾
Physical properties and	No Test	No Test	
conformance to MICD	and sources and sources and sources		T ⁽³⁾
Acceptance level			
Shock	No Test	T ⁽²⁾	No Test
Packing/Shipping	Р	Р	Р

If FCU :

(0) with PB

- (1) *PSU EM assembled with the FCU box*
- (2) PSU STM assembled with the FCU box and PB is used
- (3) *PSUFM is assembled with the FCU box*



Sub unit test matrix (SCU or MCU)

Test / Model	STM	QM1	QM2	FM
Inspection	NA	A	A	Α
Electrical tests	NA	Т	Т	Т
Functional tests	NA	Т	Т	Т
Performance tests	NA	Т	Т	Т
Vibration tests Qualification level Acceptance level	NA	NA	NA	NA
Thermal balance tests	NA	NA	NA	NA
Thermal tests Qualification level Acceptance level	NA	NA	NA	NA
EMI/EMC tests Qualification level Acceptance level	NA	NA	NA	NA
Physical properties and conformance to MICD	NA	NA	NA	NA
Shock	NA	NA	NA	NA

SCU QM1 tests are performed by the SEDI.

For QM2 and FM models, tests are performed using the means and procedures delivered by the SEDI. MCU performance tests are part of those realized by the LAM. Tests concern the inspection at delivery of the MCU in its FCU like box.



Integrated DCU / FCU test matrix

Test / Model	QM1	QM2	FM
Integration / verification	A	Α	A ⁽³⁾
Electrical tests	T	Т	T ⁽³⁾
Functional tests	T	T ⁽⁰⁾	T ⁽³⁾
Performance tests	NA	T ⁽¹⁾	T ⁽³⁾
Vibration tests	NA	No Test	No Test
Qualification level			
Acceptance level			
Shock tests	NA	No Test	No Test
Thermal balance tests	NA	No Test	No Test
Thermal vacuum tests	NA	No Test	No Test
Qualification level			
Acceptance level			
EMI/EMC tests	NA	No Test	No Test
Qualification level			2012/04/09/07 11/2 POINT 02/2001
Acceptance level			
Physical properties and	NA	NA	NA
conformance to MICD			

(0) with the PB

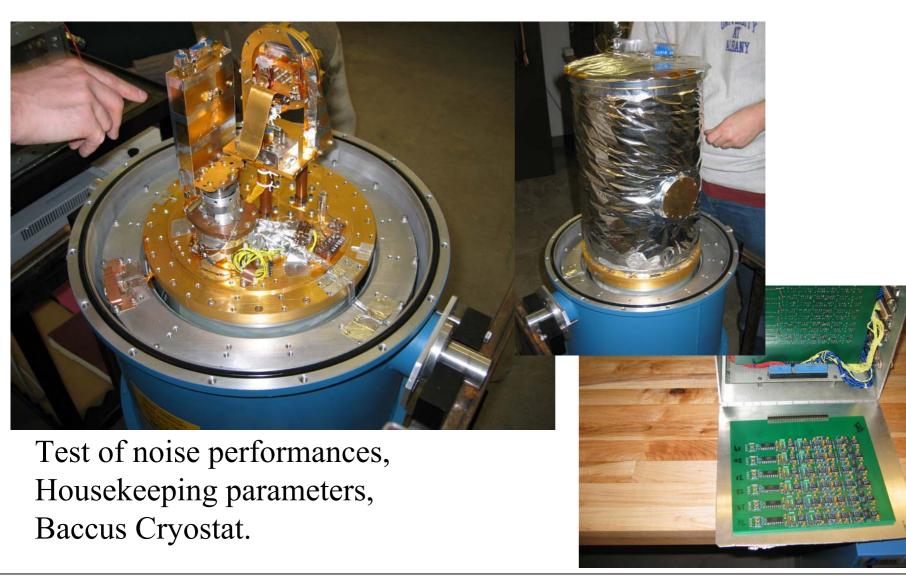
(1) the PSU EM is assembled with the FCU box

(3) the PSUFM is assembled with the FCU box





Tests with JPL Cryostat



SPIRE DRCU REVIEW

March, 4th. 2003

DRCU Programme Review 4th Feb 2003

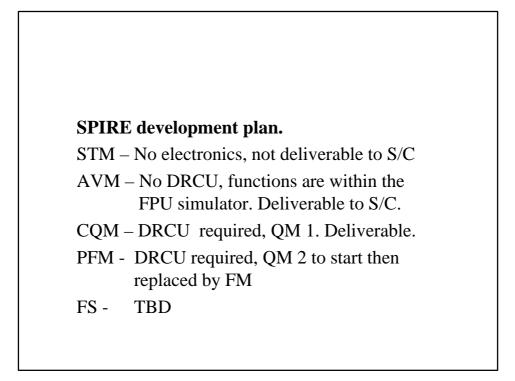
Eric Sawyer

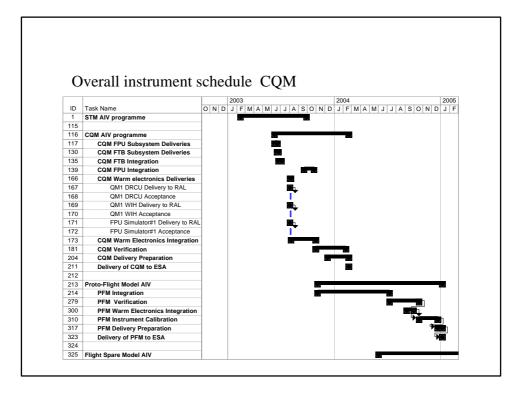
Topics

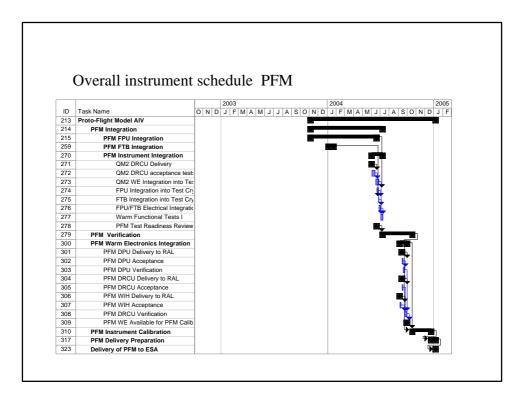
- DDR documentation
- Instrument development plan
- Instrument schedule
- Instrument status

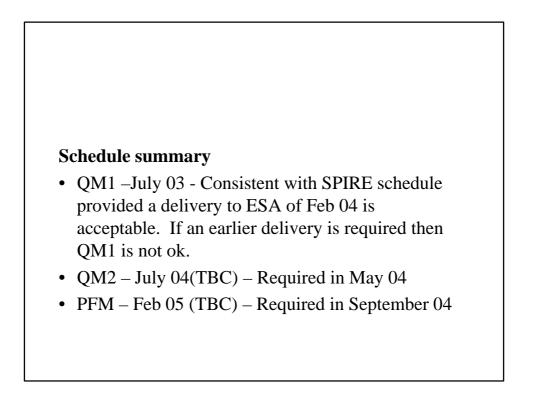
Documentation

- Review process has been going for some time
- Documents reviewed, comments sent 30 Sept 02
- Response to comments received 2 Dec 02
- Latest documents issued 18 Feb 03
- Review of documents ongoing, but almost complete
- Most comments incorporated, some minor iteration required. Document standard very good





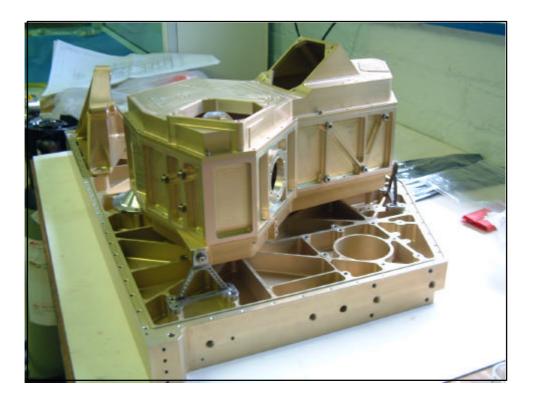




Current instrument status

- STM structure manufactured, AIT to start this month
- STM cooler and BSM at RAL, cold vibration test carried out.
- STM/CQM mirrors available
- STM detectors ready to send.
- AVM DPU complete, in test.









SPIRE DRCU Review

CEA-Saclay – March 4, 2003

DRCU Development and Procurement plan

J-L.Auguères

CEA Warm Electronics delivery commitments:



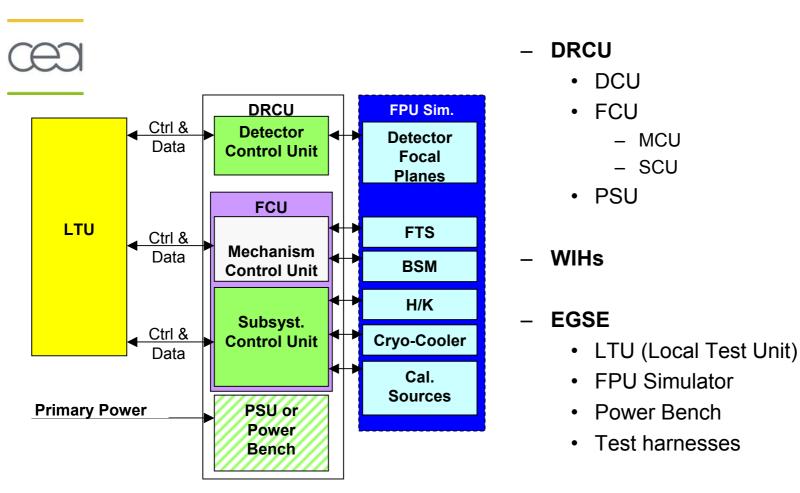
Detector Readout and Control Unit (DRCU)

- The DRCU encompasses 3 sub-units and a Power Supply (PSU):
 - Detector Control Unit (DCU)
 - Subsystem Control Unit (SCU) developed by CEA/SEDI
 - Mechanism Control Unit (MCU) developed by CNRS/LAM
- The DRCU comprises 3 boxes:
 - DCU Box.
 - FCU (Focal plane Control Unit) containing the MCU and the SCU;
 - PSU box which is bolted under the FCU box.
- Warm Interconnect Harnesses:
 - Harnesses between the DPU and the 3 DRCU sub-units.
 - Power harness between the PSU and the DCU.
- Focal Plane simulator.

developed by CEA/SIS

- - developed by CEA/SAp

 - mechanical design by CEA/SAp



• SPIRE Products:

3

DRCU Model definition:

- **STM** (commonalities with PACS WE boxes)
 - EM
 - DCU EM realised and test in collaboration with JPL/Caltech
- QM1
 - Form and fit boards in "light" boxes
 - Commercial parts
 - No redundancy
- QM2
 - Comprehensive Flight type model.
 - Intended to undergo environmental tests at Qualification level.
- FM
- FS
 - Spare units
- CEA deliveries versus ESA models:
 - AVM None
 - CQM QM1
 - FM/FS FM/FS

DRCU model features

1	~	1	
(6		
	A		1

				FCU	_		
DRCU	Mechanics	DCU	MCU	SCU	PSU	Part Grade	Perform.
BB	N/A	Yes	Yes	Yes	-	Standard	NNP
STM		Yes					N/A
QM1	Simplified	EEq(*) NCR	EEq NCR	EEq NCR	PB NCR	EEq	NNP
QM2	F -	FEq CR	FEq CR	FEq CR	STM,EM,PB CR	FEq	NNP
FM	F -	F CR	F CR	F CR	F	F	NoP
FS	F ?	F ?	F ?	F ?	F ?	F	NoP

Ext : External (Power Supply only)

EEq : Electrically Equivalent

FEq : Flight Equivalent (any grade but nominal size, consumption and performances)

F : Flight

- NCR : Cold Redundancy Not implemented
- CR : Cold Redundancy implemented
- DeP : Degraded Performance acceptable
- NNP : Near Nominal Performance
- NoP : Nominal Performance
- (*) : The number of readout channels implemented shall at least correspond to the number of detectors of the instrument CQM (photometer and spectrometer).

5

DRCU Models detailed content:



S-Syst (MI)	S-Syst (N2)	S-Sys (NB)	Part n°	STM	EM	QMI	QM2	FM	FS
т СС СС									
	DAQHF			2dum	1	1	2	2	1
					1	1	2	2	1
	BIAS			2dum				<u> </u>	1
	LIATC			1 dum	0	0	1	I	1
	LIAS			3dum	3	3	3	3	1
	LIAP			8dum	2	2	8	8	2
	BP-DCU			1 dum	1 (QM1)	1	1	1	1
	DCUBox			1	1 (QM1)	Light	1	1	
FCJ									
	SCU								
		CCHK+IF		-	-	1	2	2	1
		Temp+Heat		-	-	1	2	2	1
		BP-SCU		-	-	1?	1	1	1
	MCU			-	-	1	1	1	?
	SCUBox			-	-	Light	-	-	-
	FCUBox			-	-	Light	1	1	-
PSU				1	Lab.	PB	PB/EM	PB/1	Board
Right Hamesses									
	DROUDPU			-	-	1	2	2	-
	PSUECU			-	-	1	2	2	-
	PSUFCU			-	-	1	2	2	-
		PSUSCU		-	-	1	2	2	-
		PSUMCU		-	-	1	2	2	-

Procurement Plan:

- Boxes and Boards

• All models:

– Design

- Detailed drawings
- Realisation
- Mechanical simulations
- Thermal simulations
- Environmental tests

– Electronics parts:

- Test equipments
- QM1
- QM2, FM, FS
 - OP400 (custom packaging)
 - Others

- : in house
 - : industry
 - : industry
 - : industry
 - : in house
 - : industry
 - : Self Procurement
 - : Self Procurement
 - : Self Procurement
 - : CPPA

7

- Procurement Plan (cont.):
- œ

- Harnesses:
 - Test harnesses
 - Specification
 - Fabrication files
 - Parts (connectors, wires)
 - Realisation

- : in house
- : industry
- : Self Procurement
- : industry
- WIH (DPU to DCU, DPU to FCU, DCU to FCU power harness)
 - Specification
 - Fabrication files
 - Parts (connectors, wires)
 - Realisation
 - Environmental tests

- : in house (+ Alcatel inputs)
- : in house
- : Self Procurement
- : industry
- : industry

Procurement Plan (cont.):

- EGSEs:
 - FP Simulators (1 deliverable)
 - Specification : in house Design : in house Electronics Board realisation : industry Labview S/W : in house Standard parts (chassis, P.Sup...) : commercial procurement Integration & tests : in house LTUs (Local Test Unit). Specifications (H/W & S/W) : in house Overall Design : in house H/W detailed design & realisation : industry – S/W : in house H/W – S/W Integration & tests : in house Power Benches. - Specification : in house Overall design : in house Detailed design & realisation : industry Integration and test : industry

Procurement Plan (cont.):

DRCU QM1:

 DCU, SCU Boards: 	
– Design	: in house
 PCB routing 	: in house
– Wiring	: industry
 Electrical tests 	: in house
 Functional Tests 	: in house
 Performance Validation 	: in house
 DCU, SCU Integration & Test 	: in house
 FCU Integration & Tests 	: in house
DRCU QM2:	
 DCU, SCU Boards: 	
 PCB routing 	: in house
– Wiring	: industry
 Electrical tests 	: industry
 Functional Tests 	: in house
 Performance checking 	: in house
 DCU, SCU Integration & Test 	: In house
 FCU Integration & Tests 	: in house

• FCU Integration & Tests Environmental tests

: industry + CEA

• Procurement Plan (cont.):

– DRCU FM/FS:



- PCB routing
- Wiring
- Electrical Tests
- Functional Tests
- Performance checking
- DCU, SCU Integration & Test
- FCU Integration & Tests
- Environmental tests

- : in house
 - : industry
 - : industry
 - : industry
 - : industry
 - : TBD
 - : in house
 - : industry + CEA

Development Status:



DCU (Detector Control Unit)

- QM1:
 - Box and back-plane available.
 - Boards:
 - » 1 DAQ+IF + 1 BIAS, 1 LIA fabricated, functions and performances checked.
 - » 4 LIA under fabrication.
 - Pre-integration started:
 - » Box & Back-plane: OK
 - » Functional test OK
 - » Performance test ongoing

- FCU (Focal plane Control Unit)

- QM1:
 - Box available
 - SCU (Sub-system Control Unit)
- cf SCU presentation
- MCU (Mechanism Control Unit):
- cf MCU presentation by LAM

• Development Status (cont.):

- PSU:
 - Specification available.
 - Call for tender process started.
 - FM fab. Time 14 months (6 months to be added for contract sign off).
- Boxes:
 - I/F (external & internal) and design OK.
 - QM1 "light" boxes (DCU + FCU) available.
 - STM: Box (QM) and Mec. & Thermal mock-up boards available.
 - QM boxes:
 - DCU available (STM box)
 - FCU ready for manufacturing.

- Development Status (cont.):

– EGSEs

- Local Test Unit:
 - Specification & Architecture OK.
 - H/W: procurements OK fabrication ongoing.
 - S/W: under development.
 - 2 units will be manufactured:
 - » Availability of the 1st unit: March 03
- FP Simulator:
 - Spec. Architecture & User manual available.
 - First unit: available.
 - Second unit: fabrication started.
- Power Benches:
 - Specifications available.
 - 3 units will be manufactured
 - » 1st unit available in April 03



- Development Status (cont.):
- AIV:
 - AIV plan available.
 - AIV detailed plan and procedures under development.

– Harnesses:

- Connector procurement OK.
- Test harness specification ongoing.
- WIH
- PA/QA:
 - Internal review procedure set up.
 - Doc. List and EIDP definition OK.
 - Non conformity management procedures available.
 - DML and DPL available.

Documentation Status:

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- Review documentation:

- See the CEA document list.
- These documents have been submitted to internal reviewing process.
- Next issues submitted to internal Configuration Control.

Documentation management:

- Configuration control procedures available.
- Internal documentation database available.
- Internal acces via intranet.

DRCU Documentation Status



Management plan for the Herschel project.	SAp-FIRST-JLA-0038-01	4.0 23/01/2003
DRCU & WIH Development Plan	SAp-SPIRE-JLA-0047-01	4.0 29/01/2003
SPIRE product tree	SAp-SPIRE-DR-0094-03	1.0 21/01/2003
WBS Herschel	SAP-FIRST-DR-0043-01	2.1 30/11/2001
WBS SPIRE	SAP-FIRST-DR-0045-01	2.1 30/11/2001
SPIRE DRCU QM1master schedule	SAp-FIRST-DR-105-01	1 18/02/2003
DRCU Specifications document	SAp-SPIRE-Cca-0025-00	1.0 14/02/2003
	(SPIRE-SAP-PRJ-000461)	
DRCU ICD	SAp-SPIRE-Cca-0075-02	1.0 14/02/2003
	(SPIRE-SAP-PRJ-000451)	
DRCU DPU ICD	SAp-SPIRE-Cca-0076-02	1.0 14/02/2003
	(SPIRE-SAP-PRJ-001364)	
DCU design document	SAp-SPIRE-FP-0063-02	0.3 18/02/2003
Test plan DAQ IF	SAp-SPIRE-FP-0067-02	0.1 draft
Test plan BIAS	SAp-SPIRE-FP-0066-02	0.1 draft
Test plan LIA P	SAp-SPIRE-FP-0064-02	0.1 draft
Test plan LIA S	SAp-SPIRE-FP-0065-02	0.1 draft
SPIRE test configuration	SAp-SPIRE-LD-0015-01	3.0 08/2001
FPU simulator specs for DCU / SCU test	SIG-SPIRE-PdA-0030-01	03 14/02/2003
SPIRE LTU specifications	SAp-SPIRE-FD-0071-02	1.0 22/04/2002
DRCU AIV Plan	SAp-SPIRE-HT-0082-02	2.0 03/02/2003
DRCU EM/QM1 preliminary test plan	SAp-SPIRE-HT-0088-02	0.1 14/02/2003
SCU design document	SEDI-SCU-MM-2002-1	0.7 17/02/2003
PSU SPIRE specification	SAp-SPIRE-DS-012-02	1.1 11/12/2002
PA Plan	SAP-GERES-FI0-436-00	1.0 07/11/2000
DPL	SAp-SPIRE-NC-0061-02	1.0 13/02/2003
DML	SAp-SPIRE-NC-0060-02	1.0 13/02/2003
DMPL	SAp-SPIRE-NC-0100-02	1.0 13/02/2003
DCL	SAp-SPIRE-VM-0098-02	14 10/02/2003
Synthesis note about DRCU FMEA and reliability	SAp-SPIRE-JF-0099-03	0.1 10/02/2003
WCA (and derating??)	will be performed later	

• **ADP** (as per H/W ADP content (RAL))



Documents	QM1	FM	Comments	Doc. status QM1
shipping documents	yes	yes		
procedure for transport handling and installation	yes	yes		
C of C/Delivery Review Board MOM AI-Lists	yes	yes		
Qualification status list /test matrix	yes	yes	Inluded in DRB minutes/report	
Top level draw ings (inc. familly tree)	yes	yes		
Interface draw ings	yes	yes		SPIR-MX-5101 000
				SPIR-MX-5201 000
Functional diagrams	yes	yes	cut and paste from DRCU subsystem specs	
Electrical circuits diagrams	yes	yes	full diagrams are kept in our premices; i/f electrical diagrams	SAp-SPIR-CCa-075-02
			are included in ICD (SAp-SPIR-CCa-075-02 and SAp-SPIR-	SAp-SPIR-CCa-076-02
			CCa-076-02)	
As Built Configuration Statis List	yes	yes		
Serialised components list	n/a	yes		
List of waivers	yes	yes	To be included in ABCL	
Copies of waivers	yes	yes	To be included in ABCL	
Operational manual	yes	yes		
Historical record	yes	yes		
Logbook/ Diary of events	yes	yes		
Operating time/Cycle record	N/A	N/A		
Connector mating record	N/A	yes	included in logbook / Diary of events	
Age sensitive Items record	N/A	N/A		
Pressure Vessel History / test record	N/A	N/A		
Calibration data record	N/A	N/A		
Temporary installation record	yes	yes	included in logbook / Diary of events	
Open w ork / Deffered w ork / Open tests	if applies	if applies		
List of non-conformance reports	yes	yes	included in ABCL (if any)	
Test reports	yes	yes	list of test reports inclued in EIDP to be determined	
Proof load certificate	N/A	N/A		
Reference list of low er level ADP's	yes	yes	QM1 : MCU only; FM : MCU and PSU	
Cleanliness statement	yes	yes		
Compliance matrix	yes	yes		

DRCU Development and Procurement - QM1 Schedule

			Г		lév 03 Mar 03 Avr 03 Mai 03 Jul 03 Aoß 03
		Nom de la tâche	Début	Fin	03 10 17 24 03 10 17 24 31 07 14 21 28 05 12 19 26 02 09 16 23 30 07 14 21 28 04
		Test Equipment	01 Jan 03	11 Jul 03	
	2	Cryostat Boulder-> SAp	01 Jan 03	11 Jul 03	
	3	Power Bench SPIRE #1	01 Jan 03	16 Mai 03	
\sim	4	Harness DCU-LTU-FPU sim	01 Jan 03	11 Avr 03	
	5	LTU #1 development	01 Jan 03	01 Avr 03	
	6	FPU simulator #1 development	01 Jan 03	28 Fév 03	
-	7	Integration LTU-FPU simulator	02 Avr 03	11 Avr 03	
	8				
		DRCU QM1	01 Jan 03	30 Jul 03	
	10	DCU QM1	01 Jan 03	26 Jul 03	
	11	LIA-P 2, LIA-S 2 & 3 fabrication & Integration	01 Jan 03	11 Avr 03	
	12	DCU-LTU-FPU sim integration	14 Avr 03	22 Mai 03	
	13	Functionnal test	23 Mai 03	29 Mai 03	
	14	Performance test	30 Mai 03	12 Jui 03	
	15	Cold Performances Test	13 Jul 03	26 Jul 03	
	16	DCU QM1 Ready	26 Jul 03	26 Jul 03	26/06
	17				
	18	FCU QM1	01 Jan 03	04 Jul 03	
	19	SCU QM1	01 Jan 03	01 Mai 03	
	20	SCU development	01 Jan 03	24 Avr 03	
	21	SCU QM1 functionnal lest	25 Avr 03	01 Mai 03	
	22	SCU QM1 ready	01 Mai 03	01 Mai 03	41/05
	23				
	24	MCU	01 Jan 03	06 Mai 03	
	25	MCU QM1/0 development	01 Jan 03	15 Avr 03	
	26	MCU acceptance test	16 Avr 03	06 Mai 03	
	27	MCU QM1/0 ready	06 Mai 03	06 Mai 03	06/05
	28				
	29	FCU	07 Mal 03	04 Jul 03	
	30	SCUMCUIAT	07 Mai 03	04 Jui 03	
	31				
	32	DRCUI&T	27 Jul 03	30 Jul 03	
	33	DCU+SCU+MCU I&T	27 Jul 03	24 Jul 03	
	34	Shipping to RAL	25 Jul 03	30 Jul 03	
	35	Delivery to RAL	30 Jul 03	30 Jul 03	30/07
		2			

CEA/DSM/DAPNIA/SAp - J-L.Auguères

- Scenario 1:
 - The original development plan is kept: QM1, QM2, FM
 - Schedule risks on QM1 due to:
 - 1. Cryogenic test with the JPL test Bolometer.
 - 2. Activities within the holidays period.
 - Limited feedback for QM2: no test with the actual JPL CQM bolometers.

	2003				2004				2005	
	T1	T2	Т3	T4	T1	T2	T3	T4	T1	T2
ESA				VI 🗸	N/CQ				V FM	
SPIRE		V	DM1		VOM2		V FM			
PSU	Call		🔻 Sign off		PSU EM			V PSU F	FM	
QM1	•			•				•		
QM2										
FM										

- The QM2 development takes one year (give or take):
 - 1. QM2 board layouts have to be revised to take into account: the QM1 feedback and the use of flight component packaging.
 - 2. The test with the PSU EM.
 - 3. The environment testing at Qualification level requiring margins.
- DRCU FM available by end February 2005.

Scenario 1 (cont.)

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• Pros:

- 1. The full development is carried out minimising the risk.
- 2. The PSU EM can be tested with a flight representative model.
- 3. The PSU FM power supply can be integrated and tested with the full DRCU FM prior to its delivery.

• Cons:

1. Late availability of the DRCU FM.

Conclusion:

- 1. This scenario is the nominal one and the optimal one (as it minimises the risk).
- 2. The schedule issue could not be an issue as it is likely that other subsystems (WE or focal planes) will have comparable schedule shift (if not worse).

- Scenario 2:
 - The QM2 is cancelled and a QM1b and a PFM are built consecutively:
 - After the delivery of the QM1, a second QM1 (QM1b) is built.
 - The QM1b is identical to the QM1 (light box, Standard components, no redundancies) but all detector readout and control channels are implemented.
 - The QM1b is intended:
 - 1. To test as far as possible the PSU (EM) compatibility.
 - 2. To be used with the Instrument PFM.

	2003				2004				2005	
	T1	T2	Т3	T4	T1	T2	Т3	T4	T1	T2
ESA				V AVI	0.0/N				🔻 FM	
SPIRE		V	DM1		ОМ2		V FM			
PSU	🗸 Call		🔻 Sign off	V	PSU EM			V PSU F	FM	
QM1				•						
QM1b										
PFM										

• DRCU FM available by the end of 2004.

Scenario 2 (cont.)

• Pros:

- 1. Provides a good feedback between the QM1 and the PFM.
- 2. Provides electronics to drive the PFM Focal Plane.
- 3. The PFM delivery date is "optimised" against the PSU PFM availability date.

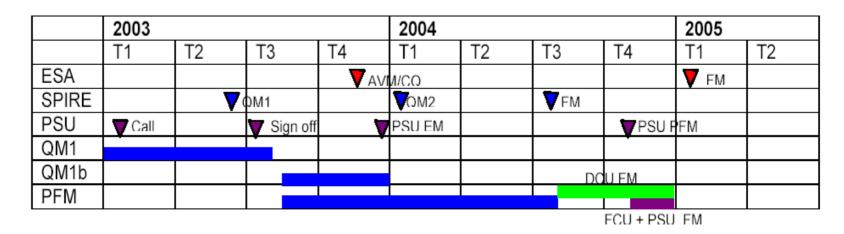
• Cons:

- 1. PFM development: high risk in case of failure at any level and especially during the environment test.
- 2. The Flight Model has to undergo the Qualification level (instead of acceptance).
- 3. There is no model to validate the electrical compatibility of the PSU with the PSU EM.

• Conclusions:

- This scenario has two major drawbacks:
 - 1. The DRCU development not in line with the PSU development.
 - 2. High risks are taken due to the PFM policy.
- Given the schedule shifting risks, the advantage to get the PFM earlier than in the case of the scenario 1 is not obvious.

- Scenario 3:
 - The QM2 is cancelled and a QM1b and a PFM are built in parallel.
 - The QM1b and its objectives are the same as in the scenario 2.



- In this case, the DRCU FM powered by a power bench could be available by October 2004 but the PSU FM has to be integrated later when available.
- DRCU FM available by the end of 2004.

• Scenario 3 (cont.):

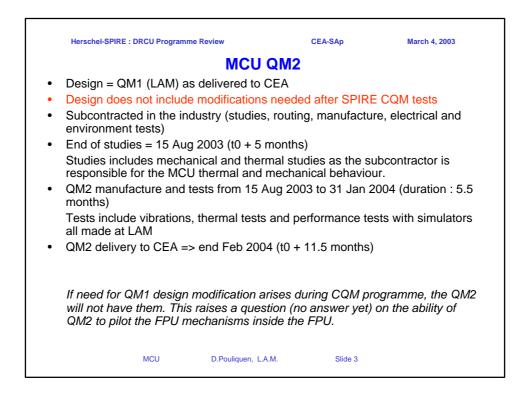
- Pros:
 - 1. Provides electronics to drive the PFM Focal Plane.
 - 2. The PFM delivery date is "optimised" against the PSU PFM availability date.
 - 3. The DCU FM can be used with the Focal Plane PFM.
 - 4. The PSU EM can be tested with a flight representative model.
- Cons:
 - 1. PFM development: high risk in case of failure at any level and especially during the environment test.
 - 2. The Flight Model has to undergo the Qualification level (instead of acceptance).
 - 3. Two models (QM1b and PFM) have to be built in parallel (resource issue).

– Conclusion:

- This scenario has two major drawbacks:
 - 1. High risks are taken due to the PFM policy.
 - 2. High workload peak when the QM1b and the PFM development are in parallel.
- Given the schedule shifting risks, the advantage to get the PFM earlier than in the case of the scenario 1 is not obvious.



Herschel-SPIRE : DRCU	Programme Review	CEA-SAp	March 4, 2003										
	MCU QM0 and QM1												
 Design + routi New model in Form & fit, ele ALTERA FPG 0.4 Commercial c Not suitable for Delivered with Delivery date 	nmunication and LTU ng+ tests at LAM + mat roduced for planning re ctrical, command interfa A including CEA DAPN omponents, no redunda or mechanisms control mechanisms simulator April 2003	tests nufacture in indust easons ace & flight function IIA Communication ancy	ons nearly Ok										
 Design + routi Tested with th control capabi Delivery date 	 Tested with the CQM mechanisms => QM0 modified for mechanism control capability => flight functions Ok at time of delivery 												



Herschel-SPIRE : DRCU Programme Review	CEA-SAp	March 4, 2003
MCU	FM & FS	
 Design = QM1 + mechanical a at LAM with the QM2 	nd thermal studies m	ade and validated
 Design does not include modif after FCU QM2 tests (tests ma manufacture i.e. vibr, thermal 	de at FCU level, afte	
 If no electrical modification w.r 	.t. QM1 as delivered	to CEA,
FM manufacture and tests manufacture + no modifs) t	•	
FM delivery to CEA => 31 months) : will not have see	•	
FS (=FM) availability at LA months) => available for th	· ·	
MCU D.Poulique	n, L.A.M. Slide 4	



SPIRE DRCU Review

CEA-Saclay – March 4, 2003

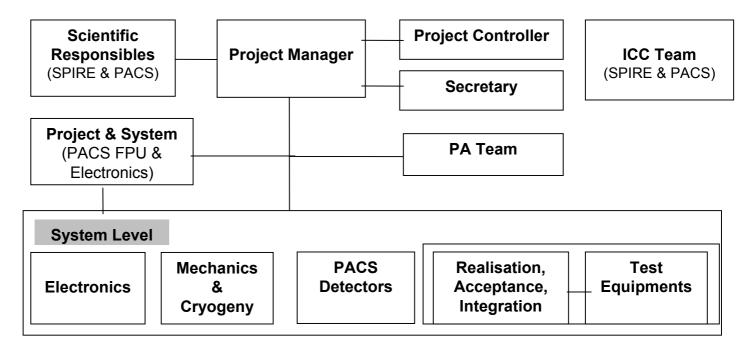
Management & Staff

J-L.Auguères

Managerial organisation:

- Two projects (SPIRE & PACS), one Herschel team.

- Main reasons:
 - Resource management flexibility.
 - Common Development.



Herschel Teams:

Project & System Team

- Members: Scientific Responsibles, the Project Manager, the PA Responsible and Team key persons.
- Check system consistency of the design and development against the system requirements.
- Discuss, sort out technical and programmatic issues, make any decisions at system level.
- Electronics Team
 - Design and development of the Electronics sub-systems.
- Mechanic and Cryogeny Team
 - Design and development of the PACS and SPIRE electronics boxes.
 - Development and setting up and maintenance of the cryogenic test facilities.
 - Design and development of the PACS Photometer Focal Plane mechanics and mounting tools.

• Herschel Teams (cont.):

- PACS detector team:
 - In charge of the overall design, the development, the test and the characterisation of the PACS Photometer Focal Plane.

- Test Equipment, Realisation and AIV team:

- Development and commissioning of the electronics ground test equipment.
- Realisation and integration of the qualification and Flight models.
- Qualification, Validation and delivery.

Product assurance team:

- Writing and maintenance of the PA documents (PAPs, method and procedures, Parts Lists,...)
- Reviews and inspections (documentation, working procedures,...)
- Selection, evaluation and procurement of the electronics parts.
- Configuration and non conformity management.
- Evaluation of radiation effects.
- Incoming inspections.
- Failure Mode Effects and Causes Analysis.

CEA Management & Staff – Herschel organisation and worksharing

		Control							SPIRE Scie
		aval	D.Ra		Manager	Project		groux	L.Vig
ICC PACS/SPIRE	ICC PA				guères	J-L.Au			
L.Vigroux			Secr		•			ntific Resp.	
ar. Bolo.) M.Sauvage	(+ Char. Bolo	and (orders)	P.Chavegra					lriguez	L.Rod
S.Madden									
Ph.André		-	Qua					ngineers	
ar. Bolo.) K.Okumura			Ххх					L.Rodriguez	
ar. Bolo.) R.Gastaud	(+ Char. Bolo	N.Colombel						C.Cara	
D.Elbaz		J.Fontignie						D.Schmitt	
J-L.Starck		V.Mauguen						C.Cara	
P.Querre		L.Dumaye	NC/PCB/Flex					D.Schmitt	EMI/EMC
GSE SPIRE & PACS	EGSE SF	AIV			PACS Ph	nanic		ronics	
F.Daly	F	onnin	C.Bc	riguez	L.Rod	irrette	T.Tou	Cara	C.C
Local Test Units	Local	sation			Focal	CS		CS	
F.Daly		(SCU excl.)	Elect. Subs.		Specification &	J.Martignac	PhFPU	E.Doumayrou	BOLC/BOLA
E.Poindron		L.Cadélis	Elect. Engin.	L.Rodriguez	Design	T.Tourrette		A.Bouère	
M.Donati		D.Schmitt	PSU	quipments	FP Test Ed	G.Dhenain		D.Schmitt	PSU
FPU Simulators	FPU S	F.Le Pelleter	Incom. Inspec.	. Fac.	BFP T	T.Tourrette	Elect. Boxes	L.Dumaye	Harnesses
P.De Antoni		E SCU	SPIRE	L.Rodriguez	Specification	G.Dhenain		IRE	SP
S.Sube		M.Mur		Y.Le Pennec	Design &	stats	Cryo	F.Pinsard	DCU
P.Beauvais		Xxxxx		T.Tourrette	Realisation	T.Tourrette	BOLG	M.Mur	SCU&I/F DPU
D.Anstett		- PU	PhF	T. Fac.	PhFPU	G.Dhenain		O.Gachelin	VHDL
O.Dubois		T.Tourrette		L.Rodriguez	Specification	T.Tourrette	Test BFPs	H.Deschamp	CCHK Board
Power Benches	Power	J.Martignac		Y.Le Pennec	Design &	T.Tourrette	Test PhFPU	E.Virique	
F.Daly		iv	A	T.Tourrette	Realisation	IRE	SP	E.Zonca	Temp. Board
C.Herviou		ronics	Electr	racterisation	Tests & Chai	T.Tourrette	Elect. Boxes	E.Zonca	Backplane
		H-E.Triou	SPIRE	PhFPU	BFP &	G.Dhenain		D.Schmitt	PSU
Bolometer (LETI)	Bolom	C.Bonnin	PACS	L.Rodriguez		gineering	Mec. Eng	L.Dumaye	Harnesses
Design & P.Agnèse		T.Tourrette	WE boxes	Y.Le Pennec		T.Tourrette		Xxxxx (A 2)	
alisation	realisatio	F.Daly	EGSE	V.Reveret		P.Perrin		nics CAD	Electror
tegration J-L.Pornin	BFP Integration	D.Schmitt	EMI/EMC	C.Bonnin				N.Devin	
J-C.Cigna		C.Herviou		T.Orduna				M.Seyranian	
3FP Test P.Agnèse	BFP Tes	Xxxxx (A2)		Xxxxx (A2)					SAp
	-		DEDU	Evaluation	Bolometer				SEDI
Cryo-Cooler (SBT)		J PACS	PIIFPU	Lvaluation					
	Cryo-Co	J PACS C.Bonnin		V.Mauguen					SIS
Cryo-Cooler (SBT) Design L.Duband	Cryo-Co				Eval. Plan				SIS SBT
Cryo-Cooler (SBT) Design L.Duband	Cryo-Co Spec. Desig Realisatio	C.Bonnin		V.Mauguen	Eval. Plan				

Annex D

Status of Comments on DRCU Documents

CERE	SPI RE Technical Note	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0
Edited: B. Swinya	ments on DCRU Documents rd/E Sawyer; <i>reply from CEA 02-12-2002</i> on documents issued for the DDR Blue	Date: 23/03/03 Page: 1 of 1

	Document	Section	Raised by	Comment Response		Follow-up/current status
GEN 1	All		EAC (PA)	There is no CIDL Configured Item Document/Drawing List. (ESA and SPIRE requirement).	Configuration Item Data List is under construction.	
2	All		EAC (PA)	There are several TBW's or will insert XYZ here when ready throughout the set of documents.	Will be corrected in next release of document set.	The DDR release?
3	All		EAC (PA)	DCU Design document, purpose and scope of this document be TBW, should not still be undefined at this stage	Document will be corrected : Action to F.PINSARD	
4	All		EAC (PA)	PA Plan is missing from this document list.	CEA has already provided its standard PA plan (sent to Kelsh DM, KING KJ, November 2000)	OK please list it

7		SPI RE	E Technica	al Note	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03)T-1399				
Edi Fur	solidated Comme ted: B. Swinyard ther comments on v comments in Bl	/E Sawyer; <i>r</i> documents	eply from CEA		Page: 2 of 2					
ID	Document	Section	Raised by	Comment	<u>.</u>	Response		Follow-up		
DRC U0	DRCU Spec. Doc.		v	Title: Detector R	Readout and Control Units					
DRC U1	DRCU Spec. Doc. SAP-PRJ-000461 (Sap-SPIRE- CCA-25-00)	2.1	BMS	Figure 2.1a has ' it should be insid	2.1a is scrambled 2.1a has "OEP" outside the FPU – ld be inside		w corrected and is no more ven in pdf format	V		
2	ditto	DRCU- REQ-45	BMS		and here's the rub! When does the filtering get specified?		powered by the FCU's CU's power filtering has no trument / system level, diated emission matters oplies.	\boldsymbol{v} fine, but on the subject of filtering, where is pre-PSD filtering specified?		
3	ditto	Fig 4.2-b	BMS	power supplies s document (DRC	igure does not accord with the r supplies specified elsewhere in the nent (DRCU-REQ-43 and DRCU- 99) and is therefore confusing –		igure does not reflect any ign and especially for ies. Shall be corrected	V		
4	<i>Ditto</i> Also applies to DRCU/DPU I/F Doc	DRCU- REQ-79 (and maybe elsewhere)	BMS	Parameter name: consistent with t In the interface of FPUTEMP# -ho more meaningfu please!	arameter names used here are not onsistent with the interface specification. In the interface doc () it uses PUTEMP# -here the temperatures have nore meaningful names – use these		Insistent with the interface specification.actual Sothe interface doc () it usesunambigPUTEMP# -here the temperatures havemeasureore meaningful names – use theseActualease!List		modified according to design in order to define sly temperature t channels. on SCU designers ilable (see attached file): O to be updated	₩ Is ICD now fixed?
5	<i>ditto</i> Also applies to DRCU/DPU I/F Doc	DRCU- REQ-83	BMS	soon as possible in the I/F parame requested by dec	e SCUSTATUS word as – it does not appear at all eter list although it can be dicated command! (cf. 14.3 and 2.2.15)	Descript	on SCU designers tion available (see attached): ICD to be updated	V		
6	ditto	DRCU- REQ-85 DRCU- REQ-86	BMS		nt called up – should be	modified to: The thermon	-85 and 86 have been netry sub-system (main ave the following channels	V		

Ţ	CRIRE	SPI RI	E Technica	al Note	Ref: SPIRE-RAL-NC Issue: 2.0 Date: 23/03/03	OT-1399		
Edi Fur	nsolidated Comi ted: B. Swinyar ther comments w comments in 2	rd/E Sawyer; <i>n</i> on documents	reply from CEA		Page: 3 of 3			
ID	Document	Section	Raised by	Comment	<u></u>	Response	I	Follow-up
						cooler related in blue) when	AD24 except for cryo- d temperature probes (text re AD21 is considered	
7	ditto	DRCU- REQ-88	BMS	Number of steps for full range operationHis over specified – PCAL requirement isbfor 256 steps – if it is convenient to haveH		HSO-CDF-ICD-013-2-0 specifies a 12- bit resolution HSO-CDF-ICD-011-2-0 specifies a 12- bit resolution		v
8	ditto	4.6.1	BMS/JD	Post regulation is shown for LIA supplies1but not for DAQ/Bias supplies.1			ors are only required for ics since input stage of the poor PSRR	Question not answered+ on motherboard
9	ditto	4.7.3	BMS	outputs of all FP (heaters; mechar	extra requirement that the GA controlled supplies hism drives etc) are kept ilisation and are kept low d otherwise.	been conside	equirement has already ered for MCU and SCU be checked for the DCU PINSARD	Text has been added to spec. in such a place as to make it partially inapplicable
10	ditto	DRCU- REQ-120	BMS		crash refer to? The DPU local to the DRCU?	This refers to	MCU S/W exclusively	v
11	ditto	4.7.5	BMS	Please check this against the Operating Modes document version 3 issued Jan 2002 as the naming of modes has been changed and we have defined two standby modes one for PHOT and one for SPEC.		Chapter 4.7.5 check	5 has been updated: please	v Bruce?
12	ditto	DRCU- REQ-122	BMS	122: The DRCU capabilities for t internal failures 122 bis: The MC capabilities to du in the sub-system	the DPU to detect	OK - Has be	en modified & added	v
13	ditto	4.9.3	BMS		inreadable – please make	OK size is do	oubled	v

	nsolidated Comr ted: B. Swinyar	nents on DCR			Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03 Page: 4 of 4)T-1399	
	ther comments of w comments in l		issued for the I	DDR			
ID	Document	Section	Raised by	Comment		Response	Follow-up
			v	it bigger.		•	• •
14	ditto	5.1.3	BMS	Are these requir	ements still relavant terface drawing exists?	Will stay in the document even if no more formally useful	v
15	ditto	8	BMS	been discussed i	igure for the DCU has in a technical note. The vered the rest of the ssion?		ν
16	ditto	11 and section 1.3	BMS	AD13 through 1 – did they go mi	7 aren't mentioned/used issing?	AD14 to AD17 have been removed from previous document issue when refreshing AD list.	ν
17	ditto	12	BMS		ct? QM1 and QM2 do not ivalent power supplies redundancy.	Table is a copy and paste of DRCU Development Plan -> document to be updated (Action : JLA)	ν
18	ditto	4.4.3	РН	REQ-85, the ran 2% source (T-S	nge for the SCAL 4% and CAL2, TSCAL4 is listed This should read 4K to	OK range update was missing (demonstrate the interest for generating ECR to keep track of requirement modification	V
19		4.2.3	JD	defined as "com noise sources re when each is ter ground, includir digitization nois	st be more precisely ubination of all DRCU ferred to the LIA inputs minated by 9K to bias ng any digital or se and contributions from U units besides the DCU).		Arose at meeting

ID	Document	Section	Raised by	Comment	Response	Follow-up
ICD	DRCU ICD	5.4.3.2.1	DKG	Include jumper connections from pins 1 to	OK - Update missing in the released	
1	SPIRE-SAP-PRJ-			21; 2 to 22, 20 to 30; 4 to 24; 5 to 25; 3 to	ICD - Has been done	
	000451			6 of J29 and also J30 to allow for		
	(Sap-SPIRE-			robustness in the SMEC Launch Latch		

7	CBIRE		E Technic		Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03	OT-1399	
Edi Fu	nsolidated Comr ited: B. Swinyar ther comments of w comments in H	d/E Sawyer; r on documents	eply from CEA	A 02-12-2002	Page: 5 of 5		
ID	D Document Section Raised by Comment					Response	Follow-up
	CCA-075-02)			drives.			

ID	Document	Section	Raised by	Comment	Response	Follow-up
DCU 1	DCU Design Description SAp-SPIRE-FP- 0063-02	3.2	BMS	What does this table mean? It is not complete.	ACTION : F. PINSARD	
2	ditto	Whole doc.	BMS	Circuit diagrams are unreadable (e.g. Picture 4-8)	ACTION : F. PINSARD	
3	ditto	4.1.3.1 4.1.6.1	BMS	I believe the offset in the first part of the picture comes from the JFETs? Please identify the source of the offset is the text or on the picture.	ACTION : F. PINSARD	
4	ditto	4.1.3.2 4.1.3.3 4.1.6.2 4.1.6.3	BMS	Can we have the transfer functions of the filters in tabular or polynomial form please. Then we can use them in the instrument models.	ACTION : F. PINSARD	
5	ditto	4.1.8.1	BMS	The description is a bit hard to follow! What is the final relationship between DATA and the amplitude of the bias that is actually output from the circuit? Is the statement about the resistors associated with the absence of the redundant cards from QM1 or does it represent a design option?	ACTION : F. PINSARD	
6	ditto	4.1.8.1 4.1.11	BMS	There is no description of how the phase of the demodulation signal is altered for each BDA module? I hope this is implemented!	ACTION : F. PINSARD	
7	ditto	4.1.12.1	BMS	Is FRAME=0 equivalent to continuous	ACTION : F. PINSARD	

Ţ	CRIRE	SPI RI	E Technic	al Note	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03)T-1399		
Edi Fur	nsolidated Commo ted: B. Swinyard ther comments on w comments in Bl	/E Sawyer; <i>I</i> documents	reply from CE	A 02-12-2002	2-12-2002 Page: 6 of 6			
ID	Document	Section	Raised by	Comment	,	Response		Follow-up
					as specified in the ICD? and START have to be e output?			
8	ditto	4.1.12.3 (Page 61)	BMS		wo values at all useful? ues as in the photometer?	ACTION : F	. PINSARD	
9	ditto	4.1.12.5	BMS			ACTION : F	. PINSARD	
10	ditto	4.1.12.7	BMS		ent design options to be	ACTION : H	. PINSARD	
-11	DCU Design Document Sap-SPIRE-FP- 0063-02 (version 0.3)	2.1.1.3	KJK	This section there are co the bias gen either a sin an adjustabl These comman implemented ICD, but I co this documen implemented	he wave bias or the DC level. Inds are in the DRCU/DPU cannot find in the they are in the design.			This is a new comment
12	Ditto	3.9.3.8	КЈК	Offsets are DRCU/DPU ICD values. This	given in the as 4 bit s section he design only			This is a new comment

ID	Document	Section	Raised by	Comment	Response	Follow-up
SCU	SCU Design	1.1.3	BMS	We don't seem to have a copy of AD5?	The AD5 document is a technical	
1	Description			SEDI-SPIRE-OG-0001-02	description of the DPU interface,	
	SEDI/SCU/MM				primarily intended to provide common	
	/2002-1				understanding for the 3 DRCU	
					implementations: DCU, MCU and	

Ţ	CBIRE	SPI RI	E Technic	al Note	Ref: SPIRE-RAL-NC Issue: 2.0 Date: 23/03/03	YT-1399		
Edi Fur	nsolidated Comr ted: B. Swinyar ther comments of w comments in I	rd/E Sawyer; <i>n</i> on documents	reply from CE	A 02-12-2002	Page: 7 of 7			
ID	Document	Section	Raised by	Comment		Response		Follow-up
2	ditto	2.1	BMS		ows "AC – why is this when there mperature channel?	KesponseSCU. This document is available.The block diagram is ambiguous. The AC channel requires 4 signals to support the On/Off and modulation controls, whereas the DC channels require only one signal for On/Off control. Will be clarified in next release.		
3	ditto	2.2 3.1 3.2	BMS	operation of the a the data frame tra i) Which takes pr Sequencer or the We wish to have even sampling rat wish the Acquisit priority. A timing useful ii) Does the FPGA	iority – the Acquisition Get Parameter request? the data in the frames at tes – therefore we would ion Sequencer to have g diagram would be A assemble a complete tit, or does it transfer the	i) There is no actual pr the "Acquisition Seque Parameter" actions, wh on a first-come first-se Analysis has shown tha interval specification (within 6ms) is guarante worst case "Get Param ii) The FPGA transfers piecewise (word per w	encer" and "Get nich are served rved basis. at the sampling all data sampled eed, even under eter" activity.	
4	ditto	3.2.1.1	BMS	Similar comment used interchangea	 Data Frame and Packet ably – please use Data means something else to 	Will be modified on ne	ext release.	
5	ditto	4.1.1 4.2.1 4.3.1	BMS	the DRCU Specif Harness Definitio	esistances are specified in fication document and the on Document. These specify the design?	The harness resistance the Sorption Pump Hea marginal at maximum resistance [With a 100 resistance, the +-9V ci 35.5 mA (500 mW dis 402 Ohm load occurs a Requires further invest	ater, which is harness Ohm harness rcuit saturates at sipation in the at 35.3 mA)].	

Cor	COPIELE			al Note	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03	T-1399		
Edi Fur	ted: B. Swinyar ther comments of w comments in H	d/E Sawyer; <i>I</i> on documents	reply from CEA		Page: 8 of 8			
ID	Document	Section	Raised by	Comment		Response		Follow-up
						relaxation (reduced resistance spec.	ction) of the harness	
6	ditto	4.1.4.5 4.2.4.4	BMS	lead resistance ca resistance does no	an that the effect of the n be ignored? The lead ot seem to be included in vhat is the dissipation cryoharness?	harness resistand dissipation shou	ater currents and ce, the cryoharness ild obviously be s is not specifically a	
7	ditto	4.2.4.1	BMS	Check with Lione	el Duband whether 4pW erms of the operation of	To my knowled by the system te	ge, still to be checked am.	
8	ditto	4.3.1	BMS		D1) specifies 6 k Ω for		account in the design. d on next release.	
9	ditto	4.4.1.2 4.4.1.3	BMS	This is an incorrect SCAL sources – t v0.92) has the con and 4% sources) v having the specifi	ct description of the he Spec. Doc (AD1 rrect specification (2% with both types of source cation as for "SCALP". ive is not required, we		account in the design. d on next release.	
10	ditto	4.8	BMS	Is this power supp with the SCU stat	oly monitoring associated is word?	on request and a parameters Scu	supplies are measured are made available in CHTp05, -n09 and – es are not checked by	
11	ditto	5.2.1	BMS	How does this wo	ork? Analogue or digital?	As stated, analo	gue.	

C	CBRE		E Technic	al Note	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03	YT-1399	
Edit Furt	solidated Comr ed: B. Swinyar her comments of v comments in H	d/E Sawyer; <i>n</i> on documents	eply from CEA		Page: 9 of 9		
ID	Document	Section	Raised by	Comment	3	Response	Follow-up
12	ditto	6.1	BMS	that all output vol held low in the re this clear in this s Also is it really tr "stateless" when that the outputs ar until commanded	ue that the SCU is it leaves reset? I hope re definitively held low otherwise?	At time of writing, the need to have outputs low at start-up was not a requirement, but this feature had been included however. This is now a requirement. Will be described more clearly in next version. The text says " the DPU is stateless once out of reset". This means that after reset, it does not keep track of command history, and always act identically under identical commands.	
13	ditto	6.2	BMS	set – FRAMECO It is reasonably us SCUSTATUS we	rgent that the ord is defined as this will detection in flight and we	FrameConf has two fields: The 1-bit "Type" field selects between "normal" and "test pattern" frames, and the "Rate" field R gives the frame rate division factor. The resulting frame repetition rate is 80/(R+1) Hz. Will be updated in next version.	
14	ditto	7.1	BMS	of AD1 v0.92 Both SCAL device	Q-89 in the latest version ces are four wire to allow f voltage and therefore on?	The cross reference table is based on DRCU spec. v0.90. The numbering has changed in spec. v0.92. Will be updated in next release.	
15	ditto	4.4	РН	Description of SC and point sources	CAL out of date, flood s no longer used	Yes. Will be updated in next release.	

Edit Furt	solidated Comme ed: B. Swinyard/ her comments on v comments in Bl	ents on DCR E Sawyer; r documents	eply from CEA	A 02-12-2002	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03 Page: 10 of 10	Т-1399	
ID	Document	Section	Raised by	Comment		Response	Follow-up
DPU -ICD 1	DRCU to DPU ICD Sap-SPIRE-CCA- 076-02	General comment	RCI at IFSI	is that, as the DRCU-DPU is the one w IFS-PRJ-0006 We always sa that we will include in t DRCU people comments, bu single docum ambiguities unnecessary	ve wrote (SPIRE- 50 of 2/4/2001). id discuss and hat document the at the need of a ment is to avoid		
2	ditto	2.1.1	RCI	with a respo with the fol Should read: DRCU subsyst	dividually reply onse word lowing ems, if dividually with with a rd with the	OK text modifed	Closed

T	CRIRE		E Technic	al Note	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03	9T-1399		
Edit Furt	asolidated Comm ted: B. Swinyard ther comments o v comments in B	d/E Sawyer; <i>r</i> n documents	reply from CEA		Page: 11 of 11			
ID	Document	Section	Raised by	Comment		Response		Follow-up
3	Ditto	2.4.1.2	RCI	DPU by transferring acknowledge or negative) response lin Should read: When a "Set_ command with received the responds to transferring acknowledge	arameter"§2.1.4.2 ??? Text modifiedceived theThe next sentence has to be modified in the same way. A "Get_paramater" command with a SYN0=1 don't generate any response. This is due to the interpretation of the SYN bit at the independently from the command id itselfarameter"SYN0=0 is subsystem he DPU by		Closed	
4	Ditto	2.1.5.1	RCI	of the CLK s and being sa on the next the CLK sign Should read: The RES sign modified on of the CLK s and being sa	the rising edge signal mpled by the DPU falling edge of al. al shall be the falling edge signal mpled by the DPU rising edge of	designed acc as given by t ago. Why a s	t to modify : H/W is ording to the first sentence his document a long time to late comment, while the existing. Must be checked rs	'next' is omitted dfrom the text – is it important?

CORRE		SPI RE Technical Note			Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03		
Consolidated Comments on DCRU Documents Edited: B. Swinyard/E Sawyer; <i>reply from CEA 02-12-2002</i> Further comments on documents issued for the DDR New comments in Blue					Date: 23/03/03 Page: 12 of 12		
ID	Document	Section	Raised by	Comment	,	Response	Follow-up
5	Ditto	2.1.5.3	RCI	Delta T1 is missing in the max command rate formula. In any case the formula is very optimistic as the actual max rate (if SYN0=0) is around 500 commands per second.		This value is given for information only. I agree as not very realistic	Not changed OK?
6	Ditto	2.2.5.2	КЈК	Add / to SetGetPhotoJfetPwr and SetGetPhotoOffset In SetGetPhotoOffset the channel number can only be 0 to 31 (not 0 to 32), which presumably correspond to channel numbers 1 to 32 in table 2.2.6.4. Similarly for SetGetSpectroOffset.		Text & value corrected for both Photometer and Spectrometer. 0 to 31 (physical address) effectively corresponds to 1 to 32 (LIA_P channel number) 0 to 23 (physical address) effectively corresponds to 1 to 24 (LIA_P channel number)	
7	Ditto	2.2.5.3	КЈК	SetGetSpectroHeaterPwr should be SetGetSpectroHeaterBias (to be consistant with Photo table)		Oops - Corrected	Closed
8	Ditto	2.2.6.1.4	КЈК	Description for SetDemodPh should be 'Set the bolometer group demodulation phase shift'		Corrected. Command acronyms also corrected to respectively SetPhotoDemaPh and GetPhotoDemoPh (Photo was missing)	Closed
9	Ditto	2.2.6.1.6	КЈК	Heading shou PhotoHeaterE consistant w 2.2.5.2.	Bias to be	Oops - Corrected	Closed

Con	Solidated Comme		E Technica U Documents	al Note	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03 Page: 13 of 13	T-1399		
Fur	ed: B. Swinyard/ her comments on comments in Bl	documents	1 0 0					
ID	Document	Section	Raised by	Comment	<u></u>	Response	I	Follow-up
10	Ditto	2.2.6.5.8	KJK	Description GetSpLWJfetV 'Get S-LW JF voltage' Description	/SS should be TET source for /SS should be		ted - Corrected	Closed
11	Ditto	2.2.6.7.1	КЈК	of the scient section 2.3. is set to 1 2 to 0 may c	the desciption the frames in 5 that if bit 3 (test) then bits only be set to 0 happens for other s?	F.PINSARD have the feel command ha splitted into 2 present defin for us!	Iress this point with but with not conclusion. I ing the definition of this s to be modified or even 2 or 3 commands; the ition is to confusing even to enhance this point	Still open, current text is still not clear
12	Ditto	2.2.7.1	КЈК	BiasDiv - se set to 0 the frequency wi What actuall Presumably s Channel_P1 t	.ll be infinite! y happens? setting		PINSARD to clarify this	Closed

T	CBIRE	SPI RI	E Technic	al Note	Ref: SPIRE-RAL-NC Issue: 2.0 Date: 23/03/03	OT-1399		
Edit Furt	solidated Comr ed: B. Swinyar her comments of comments in I	rd/E Sawyer; r	eply from CEA		Page: 14 of 14			
ID	Document	Section	Raised by	Comment	-	Response		Follow-up
13	Ditto	2.2.7.2	КЈК	BiasDiv rath DivBias?) is sampling free infinite! Wh happens? Presumably s Channel_S1 t	s set to 0 the equency will be nat actually setting	Action to F.	PINSARD to clarify this	Still open text not changed
14	Ditto	2.2.7.3	КЈК		05 and 06 are Action to F.PINSARD to clampoint ch respect to point		PINSARD to clarify this	closed
15	ditto	2.2.8.1	КЈК	Step 1: to s Bias Frequer is PhotoMClk Step 2: to s Sampling Fre parameter id (or PhotoDiv Step 3: Ther for each BDA Step 25: Why been chosen? Step 30: The for each BDA Step 38: Why been chosen?	set the Photo acy the parameter cDiv set the Photo equency the d PhotoBiasDiv vBias) ce are 448 cases a v has value EF ere are 448 cases a v has value EF	point	PINSARD to clarify this	Closed, but questions about steps 25 and 38 unanswered – see new question later
16	Ditto	2.2.8.4.1	КЈК	Step 1: Ther command Step 1: Ther command		Action to F. point	PINSARD to clarify this	Closed

Ţ	C PIRE	SPI RI	E Technic	al Note	Ref: SPIRE-RAL-NC Issue: 2.0 Date: 23/03/03	OT-1399		
Edit Fur	nsolidated Comm ted: B. Swinyar ther comments of w comments in H	d/E Sawyer; <i>r</i> on documents	eply from CEA		Page: 15 of 15			
ID	Document	Section	Raised by	Comment	,	Response	-	Follow-up
17	Ditto	2.2.15	КЈК	are missing previous ver such as DAQ	sion of the ICD, and LIA voltage this deliberate to be found	DAQ and LL more routed t the now remo Those param	A supply voltages are no through the SCU (using oved DISTRIB module). eters are transmitted as y the DCU (see §2.2.5.6: 'US)	Closed
18	Ditto	2.3.5.3.1.	КЈК	frames of Ph Array. There detector cha sampled (see 2.3.5.3.2). word at the Structure co Status. What words? Simil Frame length longer than does the tab total length	ength of 294 for otometer Full are 288 innels to be table There is one end of the Data ontaining the ADC are the other 5 arly the other as are 5 words necessary - or ole give the of the frame the length of	total length o	mn corresponds to the of the frame. Table column been corrected	Closed

Edit	solidated Comm ted: B. Swinyard	ents on DCR /E Sawyer; r	eply from CEA	A 02-12-2002	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03 Page: 16 of 16)T-1399		
	ther comments or v comments in B		issued for the	DDK				
100 10 19	Document Ditto	Section 2.3.5.3.2	Raised by KJK	order the pi in the data assume that stored in the across each CH16/LIA_P2 row in turn, top? Is it true to 144 data in correspond to and the finat correspond to And this is which they we Frame IDs 2, Is the arran	to the Photometer ne next 96 data to the MW Array al 48 data to the LW array? the order in will appear in	spectrometer analog chann multiplexed is the pixels are is obtained b ADC 6 interl the table is to According to (from John) t DRCU board - PSW 1 to 1 - PLW 1 to 4 - PMW 1 to 9 - SSW 1 to 4 - SLW 1 to 2 - T/C : To get an ans	$J22 = LIA_P9^{-}$ swer to the second part of	Follow-up Closed
						your question of the ICD. T	a please refer to the extract ables are now in colours responding to a	

Edit Furt	solidated Comm ed: B. Swinyard her comments of comments in B	ents on DCR I/E Sawyer; <i>r</i> n documents	eply from CEA	A 02-12-2002	Ref: SPIRE-RAL-NC Issue: 2.0 Date: 23/03/03 Page: 17 of 17	vT-1399		
ID	Document	Section	Raised by	Comment	<u></u>	Response		Follow-up
20	Ditto	2.3.5.3.4	KJK	I believe fr contains the reference of rather than Can you conf I would have Type T7 to c data to type position and Again the ta give the Tot rather than	a 32 bit time a the crossing, the delta time. a the delta time. a time this? b expected Frame contain similar a T6 (i.e. jiggle d error signal) able seesm to cal Frame Length	See proposal according to MCU/DCU ((20/09/2002)	heading modified to	Closed
21	Ditto	2.3.5.3.5	КЈК	25 hsk param reading of s indicates mo are availabl	This implies only meters, but my section 2.2.14 ore parameters .e. Please put a .ch parameters go	a list of 24 pa of the frame i 1 wd for leng 24wds for da + 2wds for fr check word =	th + 1 wd for frame ID + ata + wd 1 for Data Status ame time + 1 wd for	Closed

Edited: B. Swinyard/E Sawyer; reply from CEA 02-12-2002 The contract of the DDR Further comments on documents issued for the DDR New comments in Blue ID Document Section Raised by Comment Response Follow-up 22 Ditto 2.3.6 KJK I have tried to understand the reference document but I think there is more information needed to allow someone to calculate the pseudo random sequence expected. We need to know which bits are being fed back into the register and whether they are being modified before being fed back. Still open A table of the first few values for each LFSR would be useful to allow us to check our code. Please clarify whether all the data in a single frame has the same value or is a new value calculated for each data in the frame? No - a new value is calculated		onsolidated Commu	ents on DCR			Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03 Page: 18 of 18	9T-1399			
ID Document Section Raised by Comment Response Follow-up 22 Ditto 2.3.6 KJK I have tried to understand the reference document but I think there is more information needed to allow someone to calculate the pseudo random sequence expected. We need to know which bits are being fed back into the register and whether they are being modified before being fed back. Yes such a table has to be given in the ICD. Action on myself to prepare tables for DCU/MCU and SCU Yes are value for a new value is calculated	Fu	rther comments or	documents							
22 Ditto 2.3.6 KJK I have tried to understand the reference document but I think there is more information needed to allow someone to calculate the pseudo random sequence expected. We need to know which bits are being fed back into the register and whether they are being modified before being fed back. Yes such a table has to be given in the ICD. Action on myself to prepare tables for each LFSR would be useful to allow us to check our code. Please clarify whether all the data in a single frame has the same value or is a new value calculated for Please clarify whether all and whether all conducted for	Ne	ew comments in Bl	ue							
<pre>the reference document but I think there is more information needed to allow someone to calculate the pseudo random sequence expected. We need to know which bits are being fed back into the register and whether they are being modified before being fed back. A table of the first few values for each LFSR would be useful to allow us to check our code. Please clarify whether all the data in a single frame has the same value or is a new value calculated for</pre>		Document	12 1 1 1	V			Response			Follow-up
	22	Ditto	2.3.6	KJK	the reference think there information someone to co pseudo rando expected. We which bits a back into the whether they modified bef back. A table of to values for e be useful to check our co Please clari the data in has the same new value ca	the first few each LFSR would o allow us to be allow to the first few each LFSR would o allow us to be allow to be allow to be allow frame to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow to be allow	ICD. Action on m for DCU/M(yself to prepare tables CU and SCU	Still open	

Edi Fur	nsolidated Comme ted: B. Swinyard/ ther comments on w comments in Bl	ents on DCR /E Sawyer; <i>r</i> documents	reply from CEA	A 02-12-2002	Ref: SPIRE-RAL-NO Issue: 2.0 Date: 23/03/03 Page: 19 of 19)T-1399		
ID	Document	Section	Raised by	Comment		Response	Follow	<i>w</i> -up
DPU - ICD- 23	DRCU to DPU ICD Sap-SPIRE-CCA- 076-02 (version 1.0)	2.2.5.2	KJK	should be Se Command Set/ is missing	fetPwr and			
DPU - ICD- 24	Ditto	2.2.7.2	КЈК	and Vssmax n defined in t	f Vbmax, Vhmax eed to be he table as is photometer table			
DPU - ICD- 25	Ditto	2.2.8.1.1	КЈК	VSS1 etc are required par	e no longer cameters to the ss commands in			

DPU	Ditto	2.2.8.1.1	KJK	Step 25 specifies setting	
-				the detector Bias to a DC	
ICD-				value (SetPhotoBiasMode=	
26				EF). What is the purpose of	
				this? Is the DC bias mode	
				still available (see comment	
				on the DCU Design document)?	
				Similar comment for step 38	
				in section 2.2.8.1.2	

Edit Furt	asolidated Comm ted: B. Swinyar ther comments of v comments in H	nents on DCR d/E Sawyer; <i>r</i> on documents	eply from Cl	s EA 02-12-2002	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03 Page: 20 of 20	
DPU - ICD- 27	Ditto	General	KJK	that are not normal power provided. Th there is som included in	any parameters t set in the r on sequences herefore I assume me default value the FPGA code. It values should	
DPU - ICD- 28	Ditto	2.2.2	КЈК	I believe th CmdIfCtrl ar commands car of the three (DCU, MCU, S clear here a section is h	he CmdIfStat, nd SubSDelay n be sent to each e DRCU subsystems SCU). This is not as although the neaded 'DRCU cription' the for these	
DPU - ICD- 29	Ditto	2.2.2.2	КЈК	This command relevant par interface to the unit its by setting t bit in the I to zero. If control word the value of reflect the with this co current stat interface? I	d allows the rt of the command o a DRCU unit (or self) to be reset the appropriate I/F control word I read this I/F d should I expect otained to last value set ommand, or the tus of the Do I have to send ith value 7 to set being	

Com	CRIRE solidated Comr		E Technic		Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03	
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- ICD- 30	Ditto	2.2.2.3	KJK	defined as t predefined r the interface be set by co this is a co therefore be interface do no need for However, in this paramet the 'delay k reception ar This value p changes with and should k between zero response tim is, in this Please clari	response time' of ce. As it cannot ommand I assume onstant and could e defined in the ocument. There is this command. section 2.2.3 cer is defined as oetween command ad response'. oresumably n each command be a value o and the maximum me. The command case, useful.	
DPU - ICD- 31	Ditto	2.2.3	КЈК	The definiti conversion k value and ti SubSDelay is the delay pr	ion of the between received ime for parameter s not clear - is	

T	CBRE	SPI RE	Technic	al Note	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03	
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DPU - ICD- 32	Ditto	2.2.6.2 and 2.2.6.4	КЈК	between LIA/ pixel depend subsystems (BDAs). The s	the relationship (Channel and ds on external (harness and system team ble to provide	
DPU - ICD- 33	Ditto	2.2.9.3	KJK	The command specified to parameter in 4.1.1 step 5	SetBootRam is	
DPU - ICD- 34	Ditto	2.2.9.5.1	КЈК	Command SetC writeonly ar in a separat SMEC writeor	ChopLoopMode is nd so should be te section as for nly commands	
DPU - ICD- 35	Ditto	2.2.9.5.2	КЈК	missing	ChopStatus is	
DPU - ICD- 36	Ditto	2.2.9.6.1	KJK	writeonly ar		
DPU - ICD- 37	Ditto	2.2.9.6.2	КЈК		n should be d contain the ggle Readonly	

Conse		SPI RE		cal Note	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03		
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DPU - ICD- 38	Ditto	2.2.9.7	КЈК	(and their a The Set/Get)	10Param* commands		
DPU - ICD- 39	Ditto	2.2.13.2	КЈК	The frame Nu Set/GetSeqLe	umber in the ength command e from 0 to 31		
DPU - ICD- 40	Ditto	2.2.14.1.13	KJK		tion for command l is incorrect		
DPU - ICD- 41	Ditto	2.2.15	КЈК	completed be	for FrameType, us (which is		
DPU ICD- 42	Ditto	2.3.5.3.1	КЈК	A table show sampling of with respect sampling sho that we know between one another (Th: in the DCU I Description	wing the time of each channel/LIA t to the start of ould be given so w the delay pixel data and is information is		
DPU - ICD- 43	Ditto	2.3.5.3.2	KJK	The contents types (e.g.	s of other frame P-SW, PMW, P-LW to be indicated.		

Edite Furth	d: B. Swinyar	nents on DCRU rd/E Sawyer; <i>re</i> on documents i	U Document ply from CE	EA 02-12-2002	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03 Page: 24 of 24			
DPU - ICD- 44	Ditto	2.3.5.3.5	КЈК	The first for should be la	rame format abelled T4 not T5			
DPU - ICD- 45	Ditto	2.3.5.3.5	КЈК		ength given in or each frame are			
DPU ICD- 46	Ditto	2.3.5.4	КЈК	time is added the communic FPGA. In the there can be the data for available and which the for What is the the maximum	tand it the frame ed to the data by cation interface e case of the MCU e a delay between r a frame being nd the time at rame is created. requirement on for this delay? vant SAp document			

	SPI RE Technical Note				Ref: SPIRE-RAL-NOT-1399 Issue: 2.0		
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ID	Document	Section	Raised by	Comment	<u>,</u>	Response	Status
MCU-CMD-01	MCU/DCU Command List ICD and User Manual LAM/ELE/S PI.011011 (version 3.0)	General	КĴЌ	to it. However the one as applicable	becifies the DRCU/DPU ICD as applicable e DRCU/DPU ICD document specifies this ! I suggest that the DRCU/DPU ICD is the ment and references this one for parts of the ned there		
MCU-CMD-02	Ditto	3.1	КЈК	hex code to not agree wi	set command example gives the send as 90010005. This does ith the DRCU/DPU ICD, which ne command should be		
MCU-CMD-03	Ditto	3.3	КЈК	TrajModes do where the SM intialisatio (the position position etc able to read	tion of the initialisation bes not indicate the location MEC finishes. Also during on several values are found on of the endstops, the home c). It would be useful to be d these in order to monitor these 'fixed' positions		
MCU-CMD-04	Ditto	3.3	КЈК	The GetSmecs specification	Status parameter on does not indicate the each bit in the returned word		
MCU-CMD-05	Ditto	3.4	КЈК	The GetChopS specification	Status parameter on does not indicate the each bit in the returned word		

	S	SPIRE T	echnic	al Note	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0		
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ID	Document	Section	Raised by	Comment	-	Response	Status
MCU-CMD-06	Ditto	3.6.1	КЈК	telemetry fr generated at Can it be as will be gene	lear at what time the rames will start to be Eter the command is received. ssumed that the first frame erated during the next full of the MCU control loop?		
MCU-CMD-07	Ditto	3.6.1	KJK		ormats are not described		
MCU-CMD-08	Ditto	3.6.1	КЈК	packets can time. It is the table th packets are mode, even t	lear whether the 4 telemetry be requested at the same implied by the comment in nat both the BSM and the SMEC generated during FTS scan though the command scenario 4.2.2.1 does not show this.		
MCU-CMD-09	Ditto	3.7	КЈК	How is the S	SetDpuPollingTime parameter in micros?). What is the		

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ID	Document	Section	Raised by	Comment		Response	Status
MCU-CMD-10	Ditto	4.1.1	КĴК	The SetDownloadConf command is specified with a parameter field of 0xC000, but the command definition in section 3.2 does not specify a parameter. Is this parameter for ground testing only? In this case, it should be included in the document with a note indicating the different versions of the command. The SetBootRam command is specified with a parameter of 0x0001, but the command definition in section 3.2 does not specify a parameter. Is this parameter for ground testing only? In this case, it should be included in the document with a not indicating the different			
MCU-CMD-11	Ditto	4.2.1	КЈК	the launch l	ssume in the normal case that atch is unlocked once after s never relocked. Is this		
MCU-CMD-12	Ditto	4.2.1	KJK	DPU GetSmecS	ng command required from the Status (GETERRORCODE is not the document)?		
MCU-CMD-13	Ditto	4.2.2.1	КЈК	This sequence home position scan has been leaves the S TrajStartPos procedure).	te assumes the SMEC is at the on after initialisation or a en performed. However a scan SMEC at the last sition (according to this Please clarify where the the end of each type of		

	SPI RE Technical Note		Ref: SPIRE-RAL-NOT-1399 Issue: 2.0 Date: 23/03/03				
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ID	ID Document Section Raised				,	Response	Status
			by				
MCU-CMD-14	Ditto	4.3.1	KJK		sume in the normal case that		
					atch is unlocked once after		
					s never relocked. Is this		
MCU-CMD-15	Ditto	4.3.1	KJK	the case?	unchLatch command is		
WICO-CIVID-15	Dillo	4.3.1	KJK		th a parameter 0x0002, but		
					.4 the command is specified		
					rameter value of 0 or 1		
MCU-CMD-16	Ditto	4.4	KJK	Is the polli	ng command required from the		
				DPU GetSmecS	tatus (GETERRORCODE is not		
					he document)? Do we need to		
					hopStatus and GetJigStatus		
				also?			

	S	SPI RE T	echnica	al Note	Ref: SPIRE-RAL-NOT-1399 Issue: 2.0		
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ID	Document	Section	Raised	Comment		Response	Status
DEV-PLN-01	DRCU and WIH Development Plan Sap- SPIRE-JLA- 0047-01 (version 4.0)	General	by KJK	no dates att difficult to	entifies milestones but with cached. This makes it o monitor progress. Dates dded, or a separate list		
DEV-PLN-02	Ditto	General	КЈК	schedule and maintained,	ates that an overall d a master schedule are but only the QM1 schedule ovided. Where is the overall		